

INCH-POUND
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SUPERSEDING
MIL-M-38510/141A
04 May 1988

MILITARY SPECIFICATION

MICROCIRCUITS, LINEAR, DARLINGTON TRANSISTOR ARRAY, SEVEN AND EIGHT GATE, MONOLITHIC SILICON

Reactivated after July 12, 2004 and may be used for either new or existing design acquisition.

This specification is approved for use by all Departments and Agencies of the Department of Defense.

The requirements for acquiring the product herein shall consist of this specification sheet and MIL-PRF-38535.

1. SCOPE

1.1 Scope. This specification covers the detail requirements for monolithic silicon, seven and eight gate, Darlington transistor array microcircuits. Two product assurance classes and a choice of case outlines and lead finishes are provided and are reflected in the complete part number. For this product, the requirements of MIL-M-38510 have been superseded by MIL-PRF-38535, (see 6.3)

1.2 Part or Identifying Number (PIN). The PIN is in accordance with MIL-PRF-38535, and as specified herein.

1.2 Part number. The part number should be in accordance with MIL-PRF-38535, and as specified herein.

1.2.1 Device types. The device types are as follows:

<u>Device types</u>	<u>Circuit</u>
01, 02, 03, 04, 05	Darlington transistor array, seven gate
06, 07, 08, 09, 10	Darlington transistor array, eight gate

1.2.2 Device class. The device class is the product assurance level as defined in MIL-PRF-38535.

1.2.3 Case outline. The case outlines are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
E	GDIP1-T16 or CDIP2-T16	16	Dual in line
V	GDIP1-T18 or CDIP2-T18	18	Dual in line

Comments, suggestions, or questions on this document should be addressed to: Commander, Defense Supply Center Columbus, ATTN: DSCC-VAS, 3990 East Broad St., Columbus, OH 43216-5000, or email linear@dsc.dla.mil. Since contact information can change, you may want to verify the currency of this address information using the ASSIST Online database at www.dodssp.daps.mil.

1.3 Absolute maximum ratings.

Output voltage (V _{CE}).....	50 V dc
Input voltage (V _{IN})	
Device types 02, 03, 04, 07, 08, 09	30 V dc
Device types 05, 10	15 V dc
Peak collector current (I _C)	500 mA
Peak input current (I _{IN})	25 mA
Power dissipation (P _D)	1.0 W ^{1/}
Storage temperature range	-65°C to +150°C
Junction temperature (T _J)	+175°C

1.4 Recommended operating conditions.

Ambient operating temperature range (T_A) -55°C to +125°C

1.5 Power and thermal characteristics.

Package	Case outline	Maximum allowable power dissipation	Maximum θ _{JC}	Maximum θ _{JA}
16 lead dual in line	E	277 mW at T _A = +125°C	20°C/W	90°C/W
18 lead dual in line	V	330 mW at T _A = +125°C	20°C/W	75°C/W

2. APPLICABLE DOCUMENTS

2.1 General. The documents listed in this section are specified in sections 3, 4, or 5 of this specification. This section does not include documents cited in other sections of this specification or recommended for additional information or as examples. While every effort has been made to ensure the completeness of this list, document users are cautioned that they must meet all specified requirements of documents cited in sections 3, 4, or 5 of this specification, whether or not they are listed.

2.2 Government documents.

2.2.1 Specifications, standards, and handbooks. The following specifications and standards form a part of this specification to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATIONS

MIL-PRF-38535 - Integrated Circuits (Microcircuits) Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard for Microelectronics.

MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

(Copies of these documents are available online at <http://assist.daps.dla.mil/quicksearch/> or www.dodssp.daps.mil or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.3 Order of precedence. In the event of a conflict between the text of this specification and the references cited herein the text of this document shall takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

^{1/} Absolute maximum rating for power dissipation is for one Darlington pair only.

3. REQUIREMENTS

3.1 Qualification. Microcircuits furnished under this specification shall be products that are manufactured by a manufacturer authorized by the qualifying activity for listing on the applicable qualified manufacturers list before contract award (see 4.3 and 6.4).

3.2 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

3.3 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein.

3.3.1 Terminal connections and logic diagram. The terminal connections and logic diagram shall be as specified on figure 1.

3.3.2 Truth table and logic equations. The truth table and logic equations shall be as specified on figure 2.

3.3.3 Schematic circuits. The schematic circuits shall be maintained by the manufacturer and made available to the qualifying activity and the preparing activity upon request.

3.3.4 Case outlines. The case outlines shall be as specified in 1.2.3.

3.3.5 Package and sealing material. Package and sealing material shall be in accordance with MIL-PRF-38535.

3.4 Lead material and finish. The lead material and finish shall be in accordance with MIL-PRF-38535 (see 6.6).

3.5 Electrical performance characteristics. The electrical performance characteristics are as specified in table I, and apply over the full recommended ambient operating temperature range, unless otherwise specified.

3.6 Electrical test requirements. Electrical test requirements for each device class shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table III.

3.7 Marking. Marking shall be in accordance with MIL-PRF-38535.

3.7.1 Serialization. All class S devices shall be serialized in accordance with MIL-PRF-38535.

3.7.2 Correctness of indexing and markings. All devices shall be subjected to the final electrical tests specified in table II after part marking to verify that they are correctly indexed and identified by part number. Optionally, an approved electrical test may be devised especially for this requirement.

3.8 Microcircuit group assignment. The devices covered by this specification shall be in microcircuit group number 53 (see MIL-PRF-38535, appendix A).

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ unless otherwise specified	Device type	Limits		Units
				Min	Max	
Output leakage current	I_{CEX}	$V_{CE} = 50 \text{ V}$	01, 06		10.0	μA
Collector emitter saturation voltage	$V_{CE(\text{sat})}$	$I_C = 350 \text{ mA}, I_B = 850 \mu\text{A}, T_A = -55^{\circ}\text{C}$	01, 06		1.8	V
		$I_C = 200 \text{ mA}, I_B = 550 \mu\text{A}, T_A = -55^{\circ}\text{C}$			1.5	
		$I_C = 100 \text{ mA}, I_B = 350 \mu\text{A}, T_A = -55^{\circ}\text{C}$			1.3	
		$I_C = 350 \text{ mA}, I_B = 500 \mu\text{A}, T_A = +25^{\circ}\text{C}$			1.6	
		$I_C = 200 \text{ mA}, I_B = 350 \mu\text{A}, T_A = +25^{\circ}\text{C}$			1.3	
		$I_C = 100 \text{ mA}, I_B = 250 \mu\text{A}, T_A = +25^{\circ}\text{C}$			1.1	
		$I_C = 350 \text{ mA}, I_B = 500 \mu\text{A}, T_A = +125^{\circ}\text{C}$			1.8	
		$I_C = 200 \text{ mA}, I_B = 350 \mu\text{A}, T_A = +125^{\circ}\text{C}$			1.5	
		$I_C = 100 \text{ mA}, I_B = 250 \mu\text{A}, T_A = +125^{\circ}\text{C}$			1.3	
Input current	$I_{IN(\text{off})}$	$I_B \leq 25 \mu\text{A}$	01, 06		500	μA
DC forward current transfer ratio	h_{FE}	$V_{CE} = 2 \text{ V}, I_C = 350 \text{ mA}, T_A = -55^{\circ}\text{C}$	01, 06	500		
		$V_{CE} = 2 \text{ V}, I_C = 350 \text{ mA},$ $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		1000		
Clamp diode leakage current	I_R	$V_R = 50 \text{ V}$	01, 06		10.0	μA
Clamp diode forward voltage	V_F	$I_F = 350 \text{ mA}$	01, 06		2.0	V
Turn on delay	t_{PLH}	$T_A = +25^{\circ}\text{C}$, see figure 4	01, 06		750	ns
Turn off delay	t_{PHL}	$T_A = +25^{\circ}\text{C}$, see figure 4	01, 06		300	ns

TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ unless otherwise specified	Device type	Limits		Units
				Min	Max	
Output leakage current	I_{CEX}	$V_{\text{CE}} = 50 \text{ V}$, $V_{\text{IN}} = 6 \text{ V}$	02, 07		10.0	μA
Collector emitter saturation voltage	$V_{\text{CE}}(\text{sat})$	$I_C = 350 \text{ mA}$, $I_B = 850 \mu\text{A}$, $T_A = -55^{\circ}\text{C}$	02, 07		1.8	V
		$I_C = 200 \text{ mA}$, $I_B = 550 \mu\text{A}$, $T_A = -55^{\circ}\text{C}$			1.5	
		$I_C = 100 \text{ mA}$, $I_B = 350 \mu\text{A}$, $T_A = -55^{\circ}\text{C}$			1.3	
		$I_C = 350 \text{ mA}$, $I_B = 500 \mu\text{A}$, $T_A = +25^{\circ}\text{C}$			1.6	
		$I_C = 200 \text{ mA}$, $I_B = 350 \mu\text{A}$, $T_A = +25^{\circ}\text{C}$			1.3	
		$I_C = 100 \text{ mA}$, $I_B = 250 \mu\text{A}$, $T_A = +25^{\circ}\text{C}$			1.1	
		$I_C = 350 \text{ mA}$, $I_B = 500 \mu\text{A}$, $T_A = +125^{\circ}\text{C}$			1.8	
		$I_C = 200 \text{ mA}$, $I_B = 350 \mu\text{A}$, $T_A = +125^{\circ}\text{C}$			1.5	
		$I_C = 100 \text{ mA}$, $I_B = 250 \mu\text{A}$, $T_A = +125^{\circ}\text{C}$			1.3	
Input current	$I_{\text{IN(on)}}$	$V_{\text{IN}} = 17 \text{ V}$	02, 07	575	1300	μA
Input current	$I_{\text{IN(off)}}$	$I_B \leq 25 \mu\text{A}$	02, 07		500	μA
Input voltage	$V_{\text{IN(on)}}$	$V_{\text{CE}} \leq 2 \text{ V}$, $I_C = 300 \text{ mA}$, $T_A = -55^{\circ}\text{C}$	02, 07	18		V
		$V_{\text{CE}} \leq 2 \text{ V}$, $I_C = 300 \text{ mA}$, $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		13		
DC forward current transfer ratio	h_{FE}	$V_{\text{CE}} = 2 \text{ V}$, $I_C = 350 \text{ mA}$, $T_A = -55^{\circ}\text{C}$	02, 07	500		
		$V_{\text{CE}} = 2 \text{ V}$, $I_C = 350 \text{ mA}$, $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		1000		
Clamp diode leakage current	I_R	$V_R = 50 \text{ V}$	02, 07		10.0	μA
Clamp diode forward voltage	V_F	$I_F = 350 \text{ mA}$	02, 07		2.0	V
Turn on delay	t_{PLH}	$T_A = +25^{\circ}\text{C}$, see figure 4	02, 07		750	ns
Turn off delay	t_{PHL}	$T_A = +25^{\circ}\text{C}$, see figure 4	02, 07		300	ns

TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ unless otherwise specified	Device type	Limits		Units
				Min	Max	
Output leakage current	I_{CEX}	$V_{\text{CE}} = 50 \text{ V}$	03, 08		10.0	μA
Collector emitter saturation voltage	$V_{\text{CE(sat)}}$	$I_C = 350 \text{ mA}, I_B = 850 \mu\text{A}, T_A = -55^{\circ}\text{C}$	03, 08		1.8	V
		$I_C = 200 \text{ mA}, I_B = 550 \mu\text{A}, T_A = -55^{\circ}\text{C}$			1.5	
		$I_C = 100 \text{ mA}, I_B = 350 \mu\text{A}, T_A = -55^{\circ}\text{C}$			1.3	
		$I_C = 350 \text{ mA}, I_B = 500 \mu\text{A}, T_A = +25^{\circ}\text{C}$			1.6	
		$I_C = 200 \text{ mA}, I_B = 350 \mu\text{A}, T_A = +25^{\circ}\text{C}$			1.3	
		$I_C = 100 \text{ mA}, I_B = 250 \mu\text{A}, T_A = +25^{\circ}\text{C}$			1.1	
		$I_C = 350 \text{ mA}, I_B = 500 \mu\text{A}, T_A = +125^{\circ}\text{C}$			1.8	
		$I_C = 200 \text{ mA}, I_B = 350 \mu\text{A}, T_A = +125^{\circ}\text{C}$			1.5	
		$I_C = 100 \text{ mA}, I_B = 250 \mu\text{A}, T_A = +125^{\circ}\text{C}$			1.3	
Input current	$I_{\text{IN(on)}}$	$V_{\text{IN}} = 3.85 \text{ V}$	03, 07	650	1350	μA
Input current	$I_{\text{IN(off)}}$	$I_B \leq 25 \mu\text{A}$	03, 08		500	μA
Input voltage	$V_{\text{IN(on)}}$	$V_{\text{CE}} \leq 2 \text{ V}, I_C = 200 \text{ mA}, T_A = -55^{\circ}\text{C}$	03, 08	2.6		V
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 250 \text{ mA}, T_A = -55^{\circ}\text{C}$		2.8		
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 300 \text{ mA}, T_A = -55^{\circ}\text{C}$		3.0		
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 200 \text{ mA},$ $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		2.0		
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 250 \text{ mA},$ $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		2.2		
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 300 \text{ mA},$ $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		2.4		

TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ unless otherwise specified	Device type	Limits		Units
				Min	Max	
DC forward current transfer ratio	h_{FE}	$V_{CE} = 2 \text{ V}$, $I_C = 350 \text{ mA}$, $T_A = -55^{\circ}\text{C}$	03, 08	500		
		$V_{CE} = 2 \text{ V}$, $I_C = 350 \text{ mA}$, $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		1000		
Clamp diode leakage current	I_R	$V_R = 50 \text{ V}$	03, 08		10.0	μA
Clamp diode forward voltage	V_F	$I_F = 350 \text{ mA}$	03, 08		2.0	V
Turn on delay	t_{PLH}	$T_A = +25^{\circ}\text{C}$, see figure 4	03, 08		750	ns
Turn off delay	t_{PHL}	$T_A = +25^{\circ}\text{C}$, see figure 4	03, 08		300	ns

TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ unless otherwise specified	Device type	Limits		Units
				Min	Max	
Output leakage current	I_{CEX}	$V_{\text{CE}} = 50 \text{ V}$	04, 09		10.0	μA
Collector emitter saturation voltage	$V_{\text{CE(sat)}}$	$I_C = 350 \text{ mA}, I_B = 850 \mu\text{A}, T_A = -55^{\circ}\text{C}$	04, 09		1.8	V
		$I_C = 200 \text{ mA}, I_B = 550 \mu\text{A}, T_A = -55^{\circ}\text{C}$			1.5	
		$I_C = 100 \text{ mA}, I_B = 350 \mu\text{A}, T_A = -55^{\circ}\text{C}$			1.3	
		$I_C = 350 \text{ mA}, I_B = 500 \mu\text{A}, T_A = +25^{\circ}\text{C}$			1.6	
		$I_C = 200 \text{ mA}, I_B = 350 \mu\text{A}, T_A = +25^{\circ}\text{C}$			1.3	
		$I_C = 100 \text{ mA}, I_B = 250 \mu\text{A}, T_A = +25^{\circ}\text{C}$			1.1	
		$I_C = 350 \text{ mA}, I_B = 500 \mu\text{A}, T_A = +125^{\circ}\text{C}$			1.8	
		$I_C = 200 \text{ mA}, I_B = 350 \mu\text{A}, T_A = +125^{\circ}\text{C}$			1.5	
		$I_C = 100 \text{ mA}, I_B = 250 \mu\text{A}, T_A = +125^{\circ}\text{C}$			1.3	
Input current	$I_{\text{IN(on)}}$	$V_{\text{IN}} = 5 \text{ V}$	04, 09	250	500	μA
		$V_{\text{IN}} = 12 \text{ V}$		750	1450	
Input current	$I_{\text{IN(off)}}$	$I_B \leq 25 \mu\text{A}$	04, 09		500	μA
Input voltage	$V_{\text{IN(on)}}$	$V_{\text{CE}} \leq 2 \text{ V}, I_C = 125 \text{ mA}, T_A = -55^{\circ}\text{C}$	04, 09	6.0		V
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 200 \text{ mA}, T_A = -55^{\circ}\text{C}$		8.0		
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 275 \text{ mA}, T_A = -55^{\circ}\text{C}$		10.0		
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 350 \text{ mA}, T_A = -55^{\circ}\text{C}$		12.0		
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 125 \text{ mA},$ $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		5.0		
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 200 \text{ mA},$ $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		6.0		
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 275 \text{ mA},$ $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		7.0		
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 350 \text{ mA},$ $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		8.0		

TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ unless otherwise specified	Device type	Limits		Units
				Min	Max	
DC forward current transfer ratio	h_{FE}	$V_{CE} = 2 \text{ V}$, $I_C = 350 \text{ mA}$, $T_A = -55^{\circ}\text{C}$	04, 09	500		
		$V_{CE} = 2 \text{ V}$, $I_C = 350 \text{ mA}$, $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		1000		
Clamp diode leakage current	I_R	$V_R = 50 \text{ V}$	04, 09		10.0	μA
Clamp diode forward voltage	V_F	$I_F = 350 \text{ mA}$	04, 09		2.0	V
Turn on delay	t_{PLH}	$T_A = +25^{\circ}\text{C}$, see figure 4	04, 09		750	ns
Turn off delay	t_{PHL}	$T_A = +25^{\circ}\text{C}$, see figure 4	04, 09		300	ns

TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ unless otherwise specified	Device type	Limits		Units
				Min	Max	
Output leakage current	I_{CEX}	$V_{\text{CE}} = 50 \text{ V}$	05, 10		10.0	μA
Collector emitter saturation voltage	$V_{\text{CE}}(\text{sat})$	$I_C = 350 \text{ mA}, I_B = 850 \mu\text{A}, T_A = -55^{\circ}\text{C}$	05, 10		1.8	V
		$I_C = 200 \text{ mA}, I_B = 550 \mu\text{A}, T_A = -55^{\circ}\text{C}$			1.5	
		$I_C = 100 \text{ mA}, I_B = 350 \mu\text{A}, T_A = -55^{\circ}\text{C}$			1.3	
		$I_C = 350 \text{ mA}, I_B = 500 \mu\text{A}, T_A = +25^{\circ}\text{C}$			1.6	
		$I_C = 200 \text{ mA}, I_B = 350 \mu\text{A}, T_A = +25^{\circ}\text{C}$			1.3	
		$I_C = 100 \text{ mA}, I_B = 250 \mu\text{A}, T_A = +25^{\circ}\text{C}$			1.1	
		$I_C = 350 \text{ mA}, I_B = 500 \mu\text{A}, T_A = +125^{\circ}\text{C}$			1.8	
		$I_C = 200 \text{ mA}, I_B = 350 \mu\text{A}, T_A = +125^{\circ}\text{C}$			1.5	
		$I_C = 100 \text{ mA}, I_B = 250 \mu\text{A}, T_A = +125^{\circ}\text{C}$			1.3	
Input current	$I_{\text{IN(on)}}$	$V_{\text{IN}} = 3 \text{ V}$	05, 10	1180	2400	μA
Input current	$I_{\text{IN(off)}}$	$I_B \leq 25 \mu\text{A}$	05, 10		500	μA
Input voltage	$V_{\text{IN(on)}}$	$V_{\text{CE}} \leq 2 \text{ V}, I_C = 350 \text{ mA}, T_A = -55^{\circ}\text{C}$	05, 10	3.0		V
		$V_{\text{CE}} \leq 2 \text{ V}, I_C = 350 \text{ mA},$ $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		2.4		
DC forward current transfer ratio	h_{FE}	$V_{\text{CE}} = 2 \text{ V}, I_C = 350 \text{ mA}, T_A = -55^{\circ}\text{C}$	05, 10	500		
		$V_{\text{CE}} = 2 \text{ V}, I_C = 350 \text{ mA},$ $+25^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$		1000		
Clamp diode leakage current	I_R	$V_R = 50 \text{ V}$	05, 10		10.0	μA
Clamp diode forward voltage	V_F	$I_F = 350 \text{ mA}$	05, 10		2.0	V
Turn on delay	t_{PLH}	$T_A = +25^{\circ}\text{C}$, see figure 4	05, 10		750	ns
Turn off delay	t_{PHL}	$T_A = +25^{\circ}\text{C}$, see figure 4	02, 10		300	ns

TABLE II. Electrical test requirements.

MIL-PRF-38535 test requirements	Subgroups (see table III)	
	Class S devices	Class B devices
Interim electrical parameters	1	1
Final electrical test parameters	1*, 2, 3, 9	1*, 2, 3, 9
Group A test requirements	1, 2, 3, 9	1, 2, 3, 9
Group B electrical test parameters when using the method 5005 QCI option	1, 2, 3, and table IV delta limits	N/A
Group C end-point electrical parameters	1, 2, 3, and table IV delta limits	1 and table IV delta limits
Group D end-point electrical parameters	1, 2, 3	1, 2, 3

*PDA applies to subgroup 1.

4. VERIFICATION.

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not effect the form, fit, or function as described herein.

4.2 Screening. Screening shall be in accordance with MIL-PRF-38535, and shall be conducted on all devices prior to qualification and quality conformance inspection. The following additional criteria shall apply:

- a. The burn-in test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table II, except interim electrical parameters test prior to burn-in is optional at the discretion of the manufacturer.
- c. Additional screening for space level product shall be as specified in MIL-PRF-38535.

4.3 Qualification inspection. Qualification inspection shall be in accordance with MIL-PRF-38535.

DEVICE TYPES 01,02,03,04 AND 05

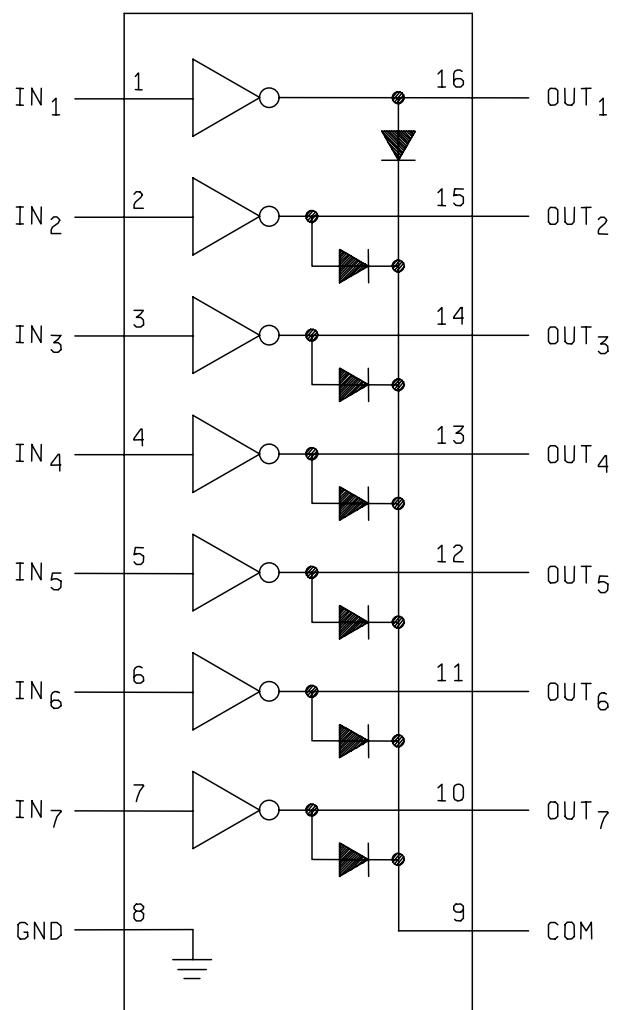
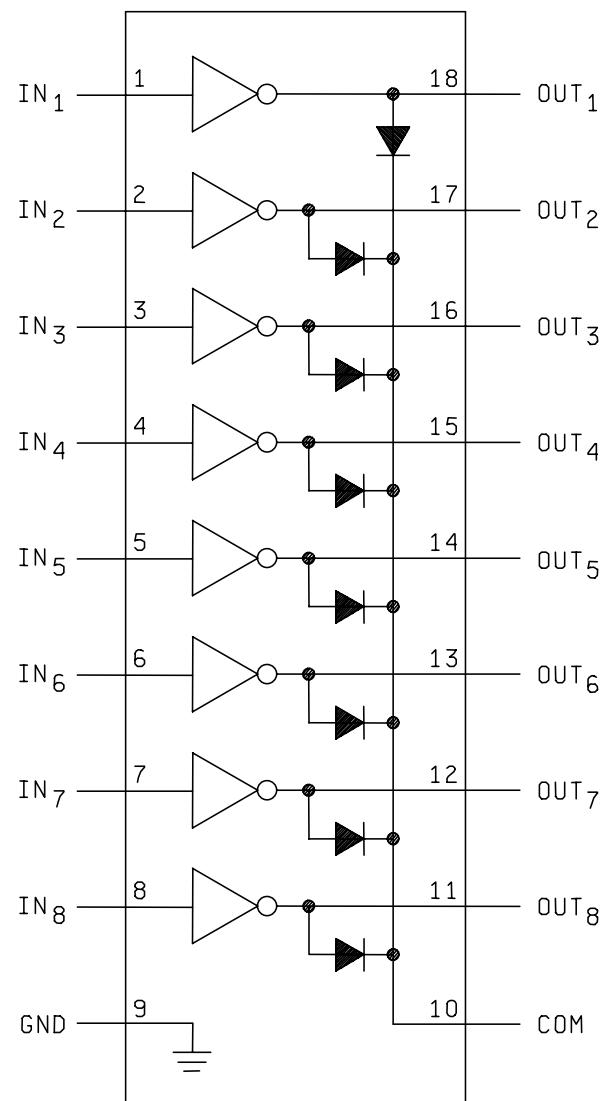


Figure 1. Terminal connections and logic diagram.

DEVICE TYPES 06,07,08,09 AND 10Figure 1. Terminal connections and logic diagram – continued.

All device types

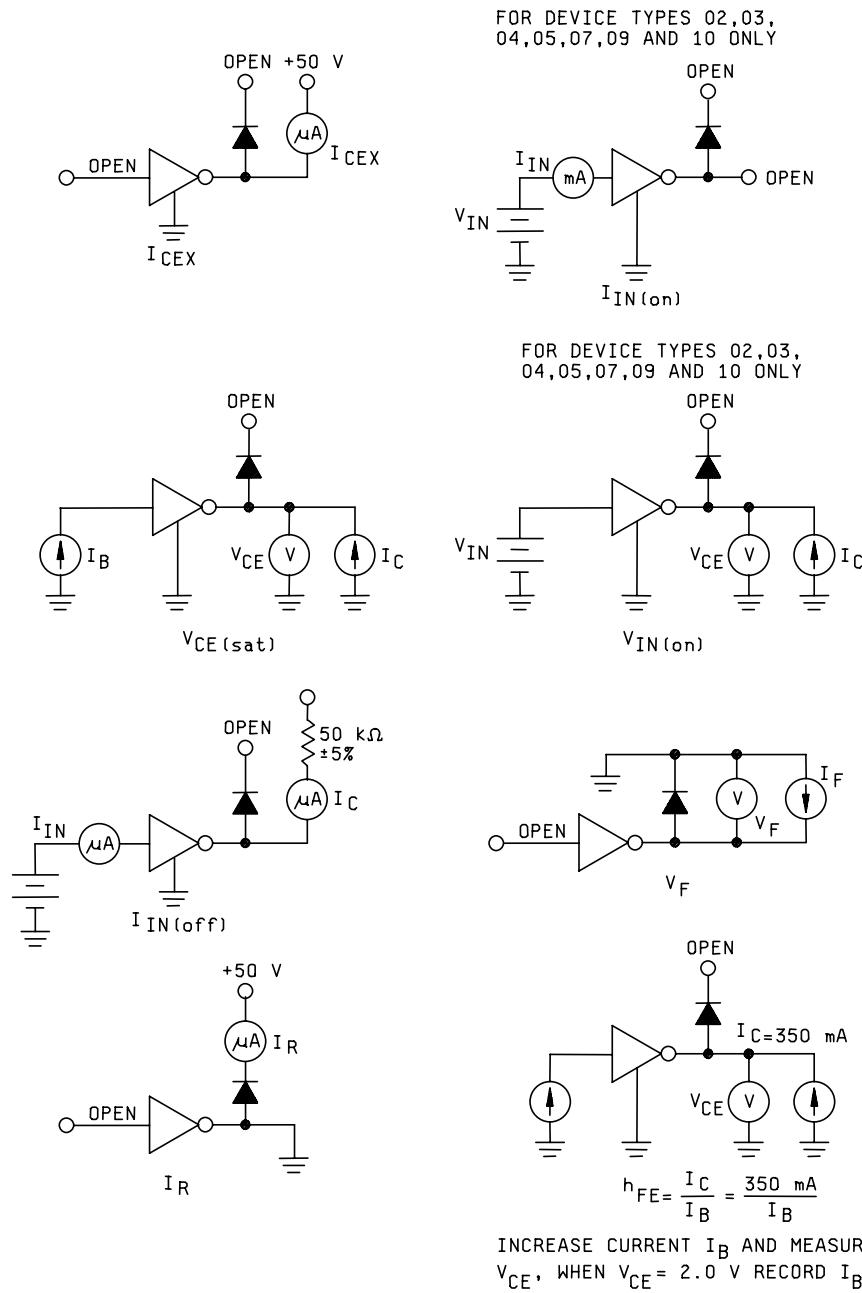
Input	Output
A	Y
0	1
1	0

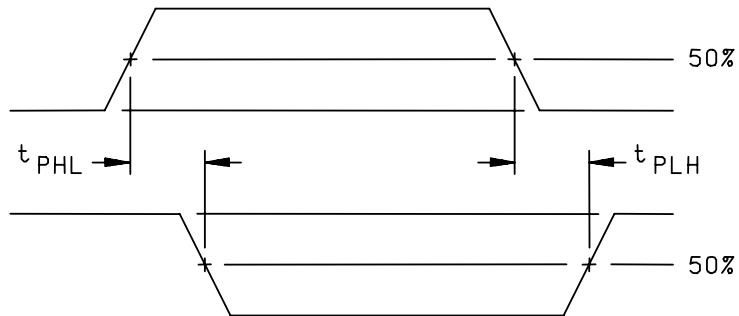
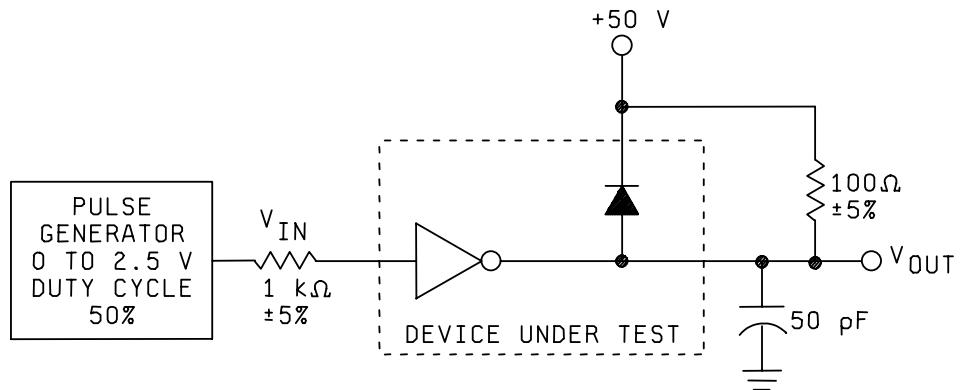
0 = Logic low level.

1 = Logic high level.

$$Y = \bar{A}.$$

FIGURE 2. Truth table and logic equation.

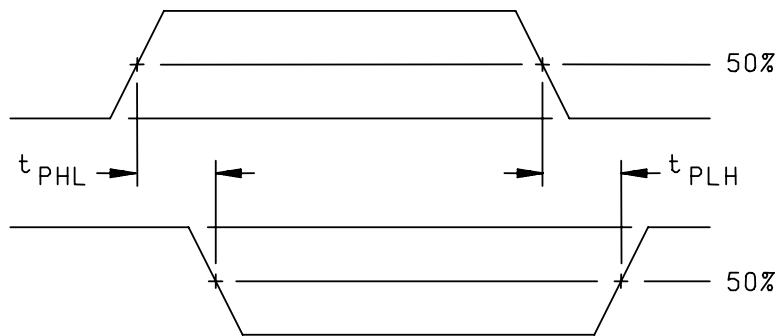
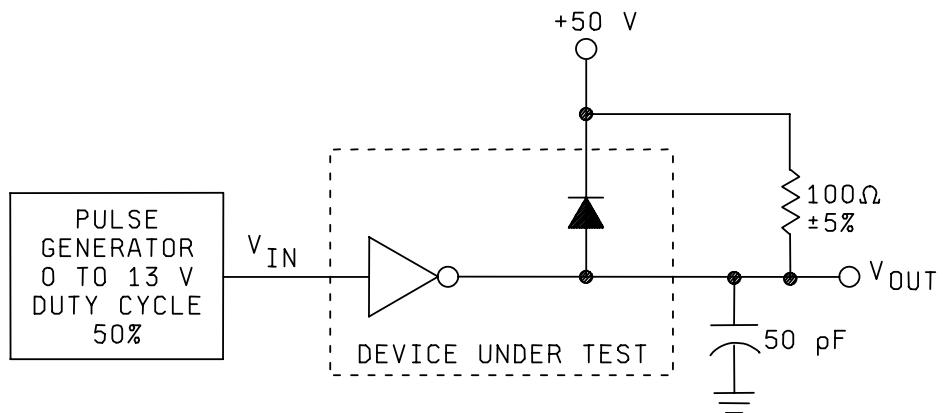
Figure 3. Test circuit for static tests .

DEVICE TYPES 01 AND 06

NOTES:

1. $f = 10 \text{ KHz}$.
2. Duty cycle = 50 percent.
3. External $1 \text{ k}\Omega$ resistor.

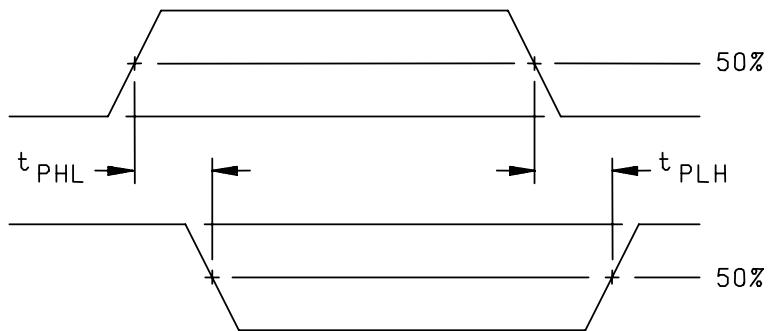
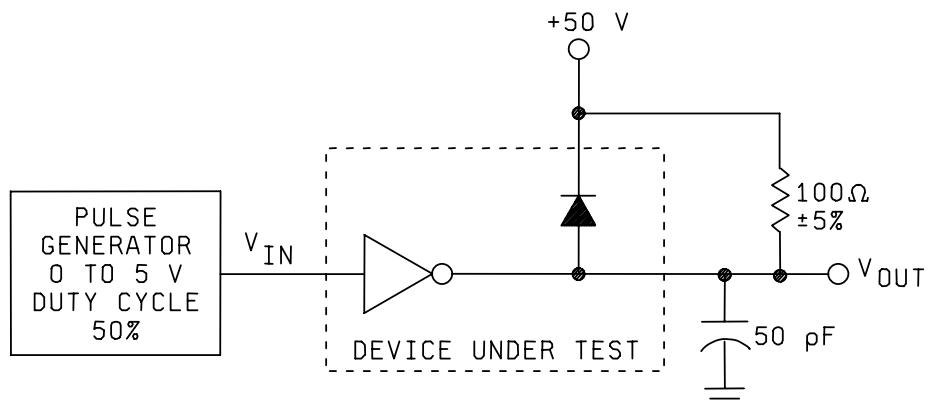
FIGURE 4. Switching time test circuits and waveforms.

DEVICE TYPES 02 AND 07

NOTES:

1. $f = 10 \text{ KHz}$.
2. Duty cycle = 50 percent.

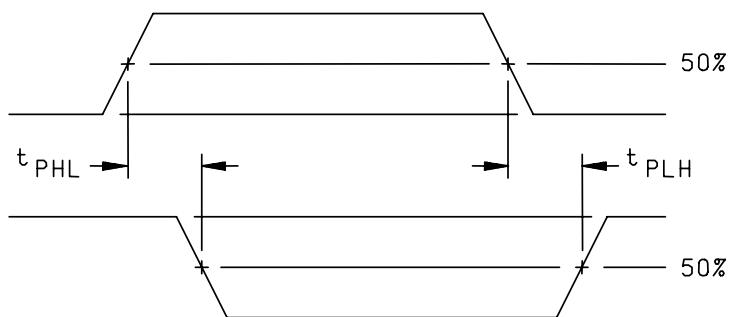
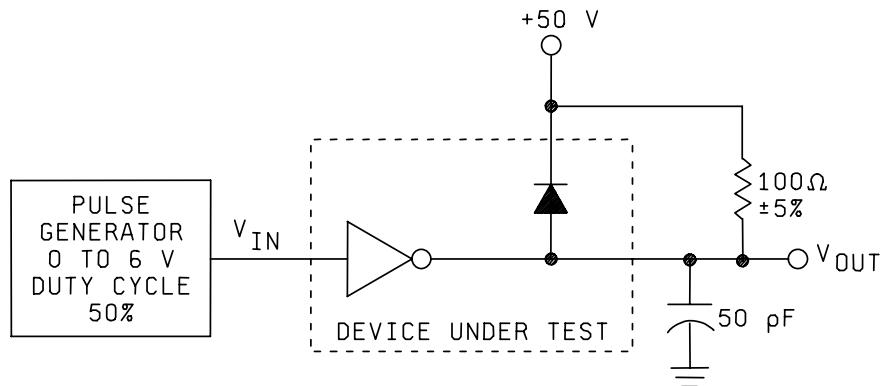
FIGURE 4. Switching time test circuits and waveforms – Continued.

DEVICE TYPES 03 AND 08

NOTES:

1. $f = 10\text{ KHz}$.
2. Duty cycle = 50 percent.

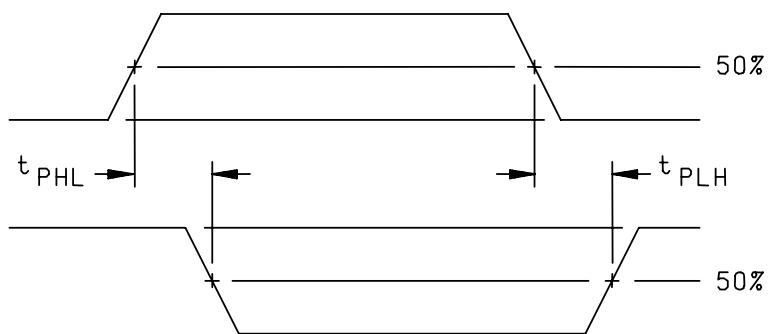
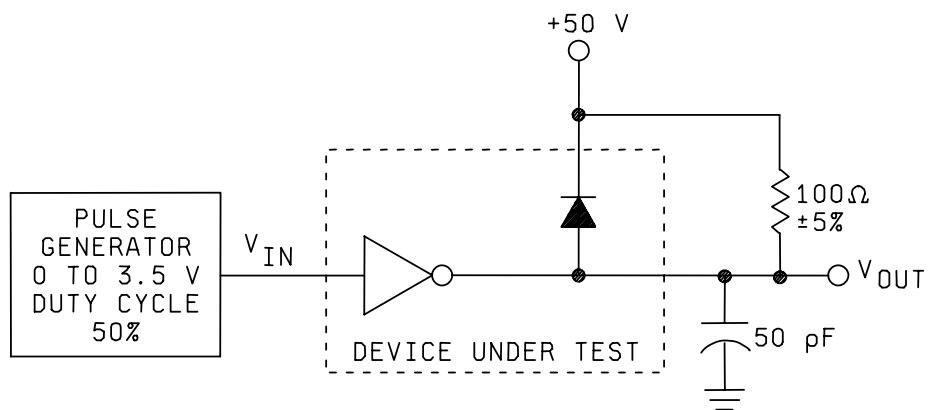
FIGURE 4. Switching time test circuits and waveforms – Continued.

DEVICE TYPES 04 AND 09

NOTES:

1. $f = 10 \text{ KHz.}$
2. Duty cycle = 50 percent.

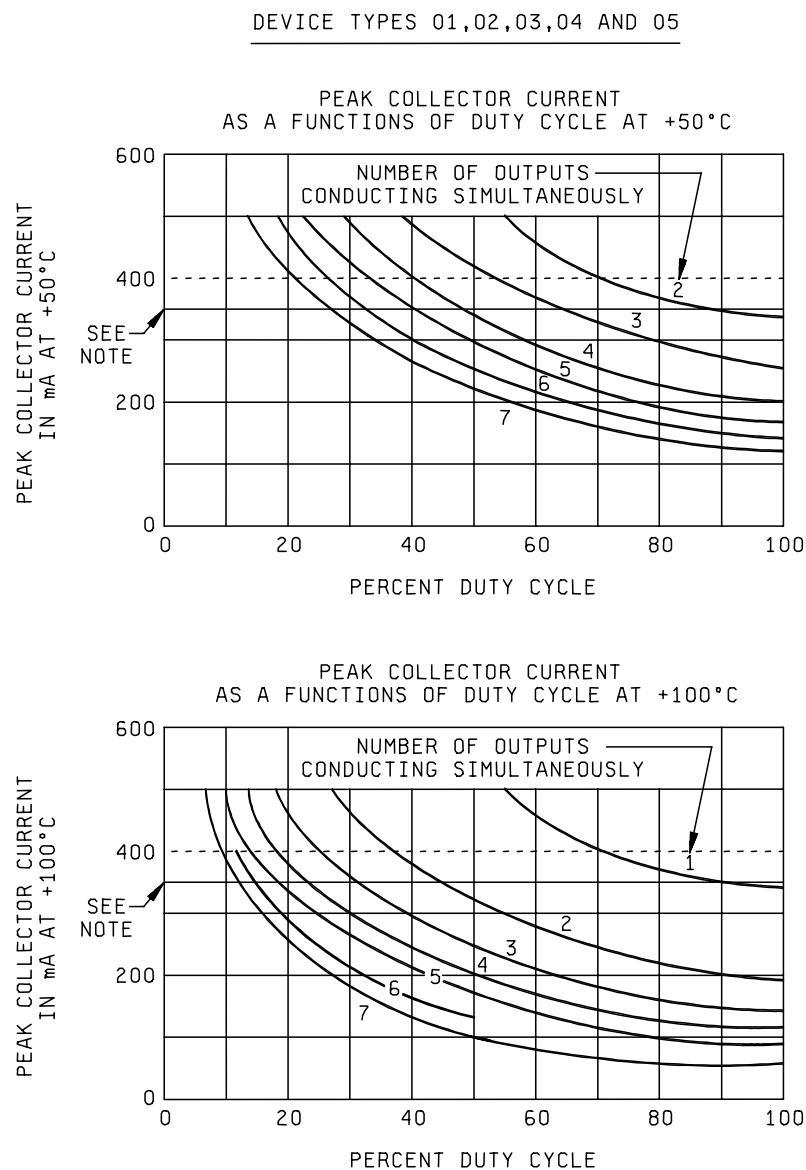
FIGURE 4. Switching time test circuits and waveforms – Continued.

DEVICE TYPES 05 AND 10

NOTES:

1. $f = 10\text{ KHz}$.
2. Duty cycle = 50 percent.

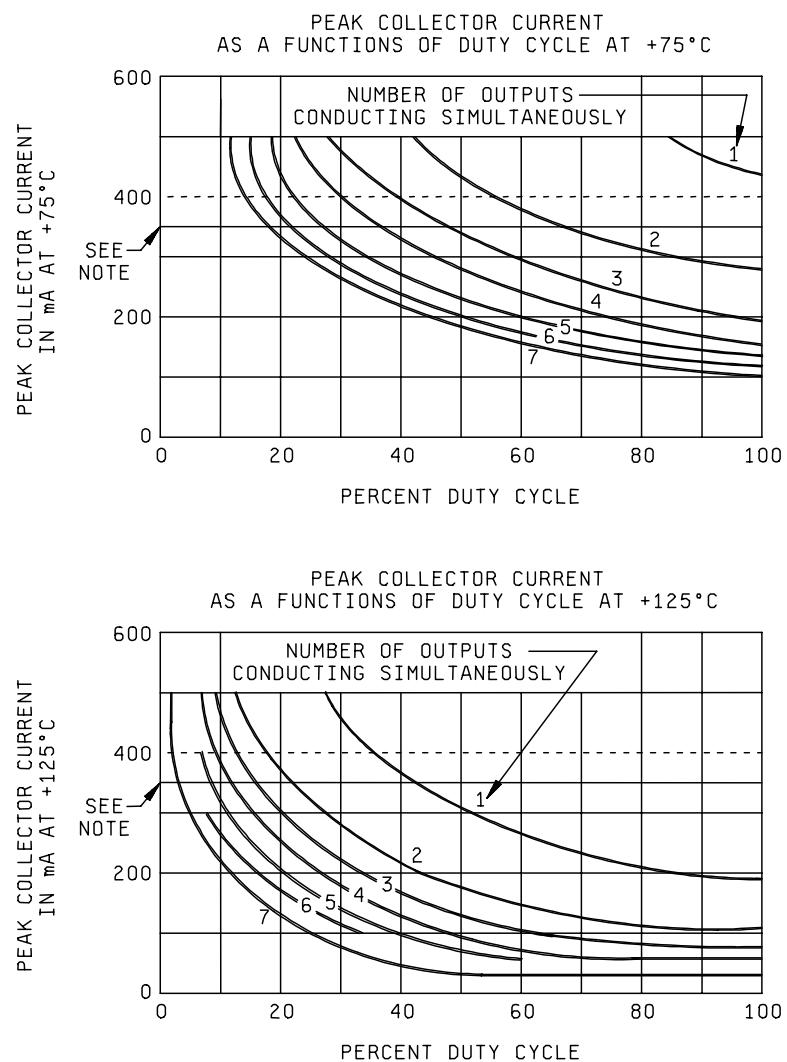
FIGURE 4. Switching time test circuits and waveforms – Continued.



* Line indicates the recommended maximum current of 350 mA.

FIGURE 5. Peak collector current as a function of duty cycle.

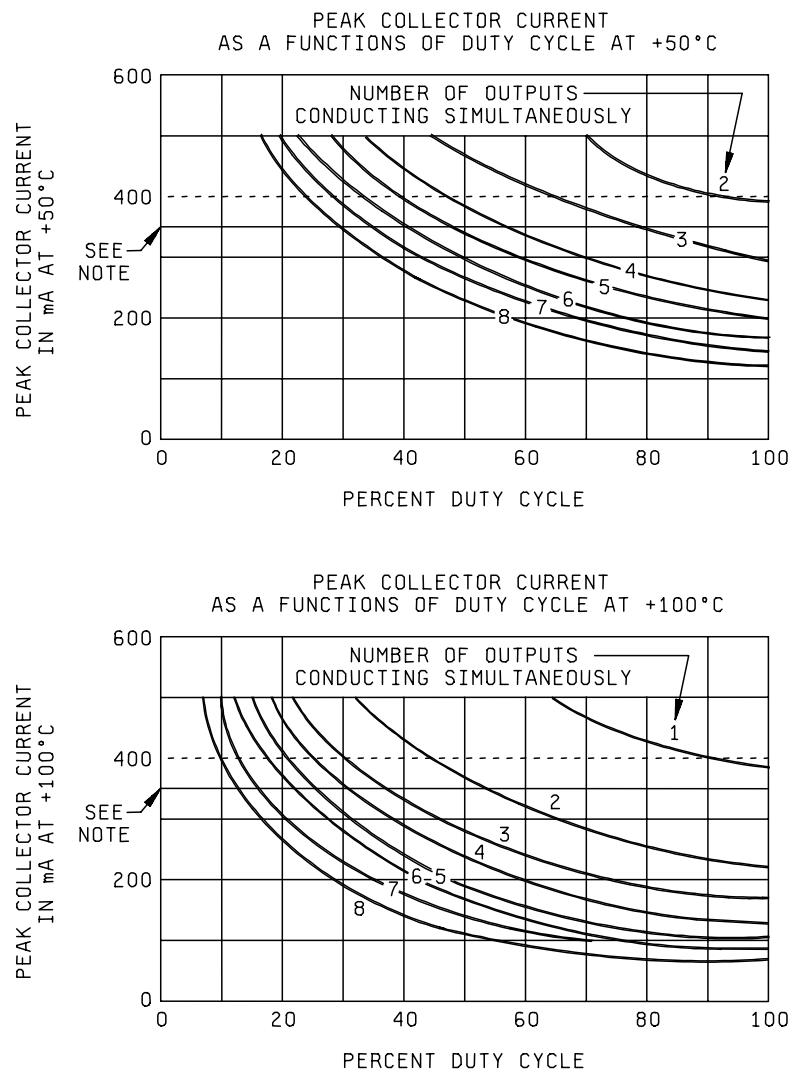
DEVICE TYPES 01,02,03,04 AND 05



* Line indicates the recommended maximum current of 350 mA.

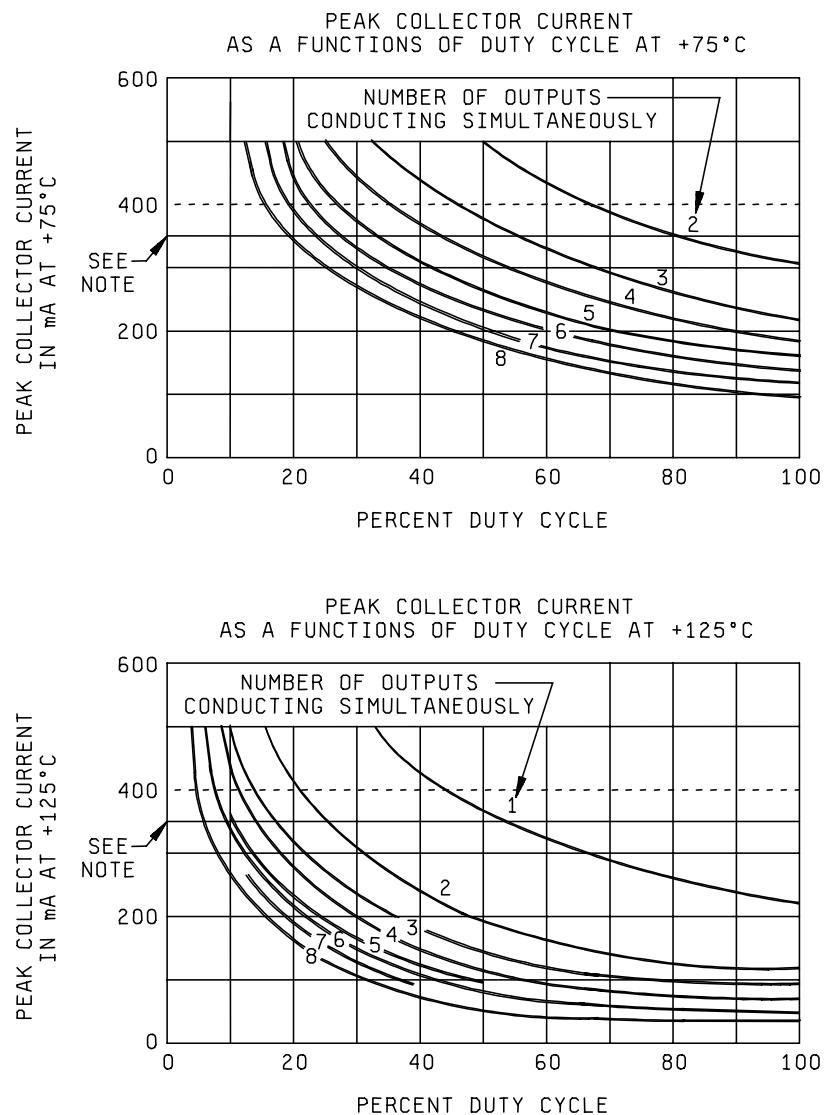
FIGURE 5. Peak collector current as a function of duty cycle – continued.

DEVICE TYPES 06,07,08,09 AND 10



* Line indicates the recommended maximum current of 350 mA.

FIGURE 5. Peak collector current as a function of duty cycle – continued.

DEVICE TYPES 06,07,08,09 AND 10

* Line indicates the recommended maximum current of 350 mA.

FIGURE 5. Peak collector current as a function of duty cycle – Continued.

TABLE III. Group A inspection for device type 01.

Subgroup	Symbol	MIL-STD-883 Test no.	MIL-method	Pin number and signal designation														Measured terminal	Limits Min	Limits Max
				1	2	3	4	5	6	7	8	9	10	11	12	13	14			
1 $T_A = +25^\circ C$	I _{cEX}	1									0 V							OUT ₁	10.0 μA	
		2									"							OUT ₂	"	"
		3									"							OUT ₃	"	"
		4									"							OUT ₄	"	"
		5									"							OUT ₅	"	"
		6									"							OUT ₆	"	"
		7									"							OUT ₇	"	"
	V _{CE(sat)}	3007	8	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 mA	350 mA	350 mA	350 mA
		9	10	11	12	13	14											OUT ₁	1.6 V	
																		OUT ₂	"	"
V _{CE(sat)}	3007	15	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 mA	200 mA	200 mA	200 mA
		16	17	18	19	20	21											OUT ₃	"	"
																		OUT ₄	"	"
																		OUT ₅	"	"
																		OUT ₆	"	"
																		OUT ₇	"	"
	V _{CE(sat)}	3007	22	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 mA	100 mA	100 mA	100 mA
		23	24	25	26	27	28											OUT ₁	1.1 V	
I _{IN(off)}	29	25 μA	30	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	250 mA	100 mA	100 mA	100 mA
		31	32	33	34	35												OUT ₂	"	"
																		OUT ₃	"	"
																		OUT ₄	"	"
																		OUT ₅	"	"
																		OUT ₆	"	"
																		OUT ₇	"	"
I _R	36																0 V	COM	10.0 μA	
	37																	COM	"	"
	38																	COM	"	"
	39																	COM	"	"
	40																	COM	"	"
	41																	COM	"	"
	42																	COM	"	"

TABLE III. Group A inspection for device type_01 – Continued.

Subgroup	Symbol	MIL-STD-883 Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit
			1	2	3	4	5	6	7	8	9	10	11	12	13	14				
1 $T_A = +25^\circ C$	V_F	43								0 V	0 V						OUT ₁	2.0	V	
		44								"	"						OUT ₂	"	"	
		45								"	"						OUT ₃	"	"	
		46								"	"						OUT ₄	"	"	
		47								"	"						OUT ₅	"	"	
		48								"	"						OUT ₆	"	"	
		49								"	"						OUT ₇	"	"	
	hFE	3003	50	IB_1						"	"						350 mA	IB ₁ -OUT ₁	1000	
2 $T_A = +125^\circ C$		51	IB_2							"	"						350 mA	IB ₂ -OUT ₂	"	
		52		IB_3						"	"						350 mA	IB ₃ -OUT ₃	"	
		53			IB_4					"	"						350 mA	IB ₄ -OUT ₄	"	
		54				IB_5				"	"						350 mA	IB ₅ -OUT ₅	"	
		55					IB_6			"	"						350 mA	IB ₆ -OUT ₆	"	
		56						IB_7		"	"						350 mA	IB ₇ -OUT ₇	"	
	I_{CEX}	57								0 V							50 V	OUT ₁	10.0	μA
		58								"	"						50 V	OUT ₂	"	
$V_{CE(sat)}$		59								"	"						50 V	OUT ₃	"	
		60								"	"						50 V	OUT ₄	"	
		61								"	"						50 V	OUT ₅	"	
		62								"	"						50 V	OUT ₆	"	
		63								"	"						50 V	OUT ₇	"	
		64	500 μA							"	"						350 mA	OUT ₁	1.8	V
		65		500 μA						"	"						350 mA	OUT ₂	"	
		66			500 μA					"	"						350 mA	OUT ₃	"	
$V_{CE(sat)}$		67				500 μA				"	"						350 mA	OUT ₄	"	
		68					500 μA			"	"						350 mA	OUT ₅	"	
		69						500 μA		"	"						350 mA	OUT ₆	"	
		70							500 μA	"	"						350 mA	OUT ₇	"	
		71	350 μA							"	"						200 mA	OUT ₁	1.5	V
		72		350 μA						"	"						200 mA	OUT ₂	"	
		73			350 μA					"	"						200 mA	OUT ₃	"	
		74				350 μA				"	"						200 mA	OUT ₄	"	
$V_{CE(sat)}$		75					350 μA			"	"						200 mA	OUT ₅	"	
		76						350 μA		"	"						200 mA	OUT ₆	"	
		77							350 μA	"	"						200 mA	OUT ₇	"	
		78	250 μA							"	"						100 mA	OUT ₁	1.3	V
		79		250 μA						"	"						100 mA	OUT ₂	"	
		80			250 μA					"	"						100 mA	OUT ₃	"	
		81				250 μA				"	"						100 mA	OUT ₄	"	
		82					250 μA			"	"						100 mA	OUT ₅	"	
$V_{CE(sat)}$		83						250 μA		"	"						100 mA	OUT ₆	"	
		84							250 μA	"	"						100 mA	OUT ₇	"	

TABLE III. Group A inspection for device type_01 – Continued.

Subgroup	Symbol	MIL-STD-883	Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit										
				IN ₁	IN ₂	3	4	5	6	7	8	9	10	11	12	13	14	15	16												
2 $T_A = +125^\circ C$	$I_{IN(off)}$	85	25 μA	86	25 μA	87	25 μA	88	25 μA	89	25 μA	90	25 μA	91	25 μA	92	25 μA	93	25 μA	94	25 μA	95	25 μA	96	25 μA	97	25 μA	98	25 μA		
	$ R $																														
	V_F	99																													
	h_{FE}	100																													
		101																													
		102																													
		103																													
		104																													
		105																													
		106	IB_1																												
3 $T_A = -55^\circ C$	I_{CEX}	113																													
		114																													
		115																													
		116																													
		117																													
		118																													
		119																													
$V_{CE(sat)}$	3007	120	850 μA	121	850 μA	122	850 μA	123	850 μA	124	850 μA	125	850 μA	126	850 μA	9	0 V	10	0 V	11	0 V	12	0 V	13	0 V	14	0 V	15	0 V	16	0 V

TABLE III. Group A inspection for device type_01 – Continued.

Subgroup	Symbol	MIL-STD-883	Test no.	Pin number and signal designation																Measured terminal	Limits Min	Limits Max	Unit
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16				
3 $T_A = -55^\circ C$	$V_{CE(\text{sat})}$	3007	127	550 μA	550 μA					0 V								200 mA	OUT ₁	1.5 V	u		
		128	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	200 mA	OUT ₂	u	u			
		129																200 mA	OUT ₃	u	u		
		130																200 mA	OUT ₄	u	u		
		131																200 mA	OUT ₅	u	u		
	$V_{CE(\text{sat})}$	132																200 mA	OUT ₆	u	u		
		133																200 mA	OUT ₇	u	u		
		3007	134	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	100 mA	OUT ₁	1.3 V	u		
		135																100 mA	OUT ₂	u	u		
		136																100 mA	OUT ₃	u	u		
4 $I_{ON(\text{off})}$	I_R	137																100 mA	OUT ₄	u	u		
		138																100 mA	OUT ₅	u	u		
		139																100 mA	OUT ₆	u	u		
		140																100 mA	OUT ₇	u	u		
		141	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	50 V	OUT ₁	500 μA	u		
	V_F	142																50 V	OUT ₂	u	u		
		143																50 V	OUT ₃	u	u		
		144																50 V	OUT ₄	u	u		
		145																50 V	OUT ₅	u	u		
		146																50 V	OUT ₆	u	u		
5 hFE	I_B	147																50 V	OUT ₇	u	u		
		148																0 V	COM	10.0 μA	u		
		149																0 V	COM	u	u		
		150																0 V	COM	u	u		
		151																0 V	COM	u	u		
	I_B	152																0 V	COM	u	u		
		153																0 V	COM	u	u		
		154																0 V	COM	u	u		
		155																0 V	COM	u	u		
		156																0 V	COM	u	u		
6 I_C	I_C	157																350 mA	OUT ₁	2.0 V	u		
		158																350 mA	OUT ₂	u	u		
		159																350 mA	OUT ₃	u	u		
		160																350 mA	OUT ₄	u	u		
		161																350 mA	OUT ₅	u	u		
		162	I_B	I_B	I_B	I_B	I_B	I_B	I_B	I_B	I_B	I_B	I_B	I_B	I_B	I_B	I_B	350 mA	I_B - OUT_1	500			
		163																350 mA	I_B - OUT_2	u	u		
7 I_E	I_E	164																350 mA	I_B - OUT_3	u	u		
		165																350 mA	I_B - OUT_4	u	u		
		166																350 mA	I_B - OUT_5	u	u		
		167																350 mA	I_B - OUT_6	u	u		
		168																350 mA	I_B - OUT_7	u	u		

TABLE III. Group A inspection for device type_01 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation														Measured terminal	Limits	Min	Max	Unit	
				1	2	3	4	5	6	7	8	9	10	11	12	13	14						
9 $T_A = +25^\circ\text{C}$	tpLH Fig. 4	3003	169	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	GND	COM	OUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	OUT	OUT	ns	
			170	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	0V	"	"	"	"	"	"	"	IN ₁ -OUT ₁	"	"	"	
			171	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₂ -OUT ₂	"	"	"	
			172	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₃ -OUT ₃	"	"	"	
			173	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₄ -OUT ₄	"	"	"	
			174	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₅ -OUT ₅	"	"	"	
			175	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₆ -OUT ₆	"	"	"	
	tpHL Fig. 4	3003	176	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	"	"	"	"	"	"	"	"	IN ₇ -OUT ₇	"	"	"	
			177	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT	OUT	OUT	OUT	ns
			178	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₁ -OUT ₁	"	"	"	
			179	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₂ -OUT ₂	"	"	"	
			180	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₃ -OUT ₃	"	"	"	
			181	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₄ -OUT ₄	"	"	"	
			182	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₅ -OUT ₅	"	"	"	

NOTE: Pins not designated are open.

TABLE III. Group A inspection for device type 02.

Subgroup	Symbol	MIL-STD-883 Test no.	Pin number and signal designation														Measured		Limits			
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	terminal	Min	Max	Unit
1 $T_A = +25^\circ C$	IcEX	1								0 V							50 V		OUT1	10.0 μA		
		2								"									OUT2	"		
		3								"									OUT3	"		
		4								"									OUT4	"		
		5								"									OUT5	"		
		6								"									OUT6	"		
		7								"									OUT7	"		
		VCE(sat)	3007	8	500 μA	500 mA	350 mA	350 mA	350 mA	V												
			9	10	11	12	13	14											OUT1	1.6		
																			OUT2	"		
VCE(sat)	3007	15	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 mA	350 mA	350 mA	350 mA	350 mA		
		16																	OUT3	"		
		17																	OUT4	"		
		18																	OUT5	"		
		19																	OUT6	"		
		20																	OUT7	"		
		21																				
		VCE(sat)	3007	22	250 μA	200 mA	200 mA	200 mA	200 mA													
			23	24	25	26	27	28											OUT1	1.3 V		
																			OUT2	"		
IN(on)	36	29	17 V	30	17 V	31	17 V	32	17 V	33	17 V	34	17 V	35	17 V	17 V	17 V	17 V	17 V	17 V	17 V	
																			IN1	575 μA		
																			IN2	"		
																			IN3	"		
																			IN4	"		
																			IN5	"		
																			IN6	"		
																			IN7	"		
IN(off)	36	37	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	50 V	50 V	50 V	50 V		
		38																	OUT1	500 μA		
		39																	OUT2	"		
		40																	OUT3	"		
		41																	OUT4	"		
		42																	OUT5	"		
																			OUT6	"		
																			OUT7	"		

TABLE III. Group A inspection for device type_02 – Continued.

Subgroup	Symbol	MIL-STD-883 Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit	
			1	2	3	4	5	6	7	8	9	10	11	12	13	14					
1 $T_A = +25^\circ C$	$V_{IN(on)}$	43	13 V	44	13 V	45	13 V	46	13 V	47	13 V	48	13 V	49	13 V	50	50 V	0 V	300 mA	300 mA	
	I_R	51		52		53		54		55		56					0 V	0 V	0 V	0 V	
	V_F	57															0 V	0 V	0 V	0 V	
	hFE	61		62		63		64	IB_1	65	IB_2	66	IB_3	67	IB_4	68	IB_5	IB_6	IB_7	350 mA	
	$V_{CE(sat)}$	70		71		72		73		74		75		76		77	78	0 V			
	I_{CEX}	79		80		81		82		83		84						500 μA	500 μA	500 μA	500 μA
																		350 mA	350 mA	350 mA	350 mA
																		350 mA	350 mA	350 mA	350 mA
																		350 mA	350 mA	350 mA	350 mA
																		350 mA	350 mA	350 mA	350 mA
2 $T_A = +125^\circ C$																		OUT ₁	OUT ₂	OUT ₃	OUT ₄
																		OUT ₅	OUT ₆	OUT ₇	OUT ₇
																		IB ₁ -OUT ₁	IB ₂ -OUT ₂	IB ₃ -OUT ₃	IB ₄ -OUT ₄
																		IB ₅ -OUT ₅	IB ₆ -OUT ₆	IB ₇ -OUT ₇	IB ₇ -OUT ₇
																		1000	1000	1000	1000
																		50 V	50 V	50 V	50 V
																		OUT ₁	OUT ₂	OUT ₃	OUT ₄

TABLE III. Group A inspection for device type 02 – Continued.

Subgroup	Symbol	MIL-STD-883	Test no.	Pin number and signal designation																Measured terminal	Limits Min	Limits Max	Unit
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16				
$T_A = +125^\circ C$	$V_{CE(sat)}$	3007	85	350 μA	350 μA						0 V								200 mA	OUT ₁	1.5 V	u	
		86	350 μA	350 μA							u								200 mA	OUT ₂	u	u	
		87			350 μA						u								200 mA	OUT ₃	u	u	
		88				350 μA					u								200 mA	OUT ₄	u	u	
		89					350 μA				u								200 mA	OUT ₅	u	u	
	$V_{CE(sat)}$	90	91								350 μA								200 mA	OUT ₆	u	u	
		92	250 μA		250 μA						u								100 mA	OUT ₇	u	u	
		93	94			250 μA					u								100 mA	OUT ₁	1.3 V	u	
		95	96				250 μA				u								100 mA	OUT ₂	u	u	
		97	98					250 μA			u								100 mA	OUT ₃	u	u	
$I_{IN(on)}$	$I_{IN(off)}$	99	100	17 V	17 V	17 V	17 V	17 V	17 V	17 V	17 V	17 V	17 V	17 V	17 V	17 V	17 V	17 V	50 V	IN ₁	575 V	1300 V	
		101																		IN ₂	u	u	
		102																		IN ₃	u	u	
		103																		IN ₄	u	u	
		104																		IN ₅	u	u	
		105																		IN ₆	u	u	
		106	25 μA																	IN ₇	u	u	
	$V_{IN(on)}$	107	108	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	50 V	OUT ₁	500 μA	u		
		109	110																OUT ₂	u	u		
		111	112																OUT ₃	u	u		
		113	114	13 V	13 V	13 V	13 V	13 V	13 V	13 V	13 V	13 V	13 V	13 V	13 V	13 V	13 V	13 V	300 mA	OUT ₄	u	u	
		115	116																OUT ₅	u	u		
	I_R	117	118																OUT ₆	u	u		
		119	120																OUT ₇	u	u		
		121	122																				
		123	124																				
		125	126																				

TABLE III. Group A inspection for device type 02 – Continued.

Subgroup	Symbol	MIL-STD-883 Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit	
			1	2	3	4	5	6	7	8	9	10	11	12	13	14					
2 $T_A = +125^\circ C$	V_F	127 128 129 130 131 132 133	IN_1 IN_2 IN_3 IN_4 IN_5 IN_6 IN_7							0 V	0 V					OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇	2.0 “ “ “ “ “ “	V “ “ “ “ “ “ “
	hFE	3003 134 135 136 137 138 139 140	IB_1 IB_2 IB_3 IB_4 IB_5 IB_6 IB_7													350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	IB ₁ -OUT ₁ IB ₂ -OUT ₂ IB ₃ -OUT ₃ IB ₄ -OUT ₄ IB ₅ -OUT ₅ IB ₆ -OUT ₆ IB ₇ -OUT ₇	1000 “ “ “ “ “ “		
	I_{CEX}	141 142 143 144 145 146 147								0 V	0 V						50 V 50 V 50 V 50 V 50 V 50 V 50 V	50 V 50 V 50 V 50 V 50 V 50 V 50 V	OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇	10.0 “ “ “ “ “ “	μA “ “ “ “ “ “
	$V_{CE(sat)}$	3007 148 149 150 151 152 153 154	$850 \mu A$ 850 μA													350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇	1.8 “ “ “ “ “ “ “	V “ “ “ “ “ “ “	
	$V_{CE(sat)}$	3007 155 156 157 158 159 160 161	$550 \mu A$ 550 μA													200 mA 200 mA 200 mA 200 mA 200 mA 200 mA 200 mA 200 mA	200 mA 200 mA 200 mA 200 mA 200 mA 200 mA 200 mA 200 mA	OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇	1.5 “ “ “ “ “ “ “	V “ “ “ “ “ “ “	
	$V_{CE(sat)}$	3007 162 163 164 165 166 167 168	$350 \mu A$ 350 μA													100 mA 100 mA 100 mA 100 mA 100 mA 100 mA 100 mA 100 mA	100 mA 100 mA 100 mA 100 mA 100 mA 100 mA 100 mA 100 mA	OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇	1.3 “ “ “ “ “ “ “	V “ “ “ “ “ “ “	

TABLE III. Group A inspection for device type 02 – Continued.

Subgroup	Symbol	MIL-STD-883 Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit
			1	2	3	4	5	6	7	8	9	10	11	12	13	14				
$T_A = -55^\circ C$	$I_{IN(on)}$	169	17 V							0 V							IN1	575	1300	μA
		170	17 V	17 V						"							IN2	"	"	"
		171								"							IN3	"	"	"
		172								"							IN4	"	"	"
		173								"							IN5	"	"	"
		174								"							IN6	"	"	"
		175								"							IN7	"	"	"
	$I_{IN(off)}$	176	25 μA	25 μA													50 V	50 V	500	μA
		177															OUT1	OUT2	OUT3	"
		178															OUT4	OUT5	OUT6	"
$V_{IN(on)}$		179															OUT7			
		180																		
		181																		
		182																		
		183	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	300 mA	300 mA	300 mA	300 mA
		184															300 mA	300 mA	300 mA	300 mA
		185															300 mA	300 mA	300 mA	300 mA
		186															300 mA	300 mA	300 mA	300 mA
		187															300 mA	300 mA	300 mA	300 mA
		188															300 mA	300 mA	300 mA	300 mA
R		189															300 mA	300 mA	300 mA	300 mA
		190															300 mA	300 mA	300 mA	300 mA
		191															300 mA	300 mA	300 mA	300 mA
		192															300 mA	300 mA	300 mA	300 mA
		193															300 mA	300 mA	300 mA	300 mA
		194															300 mA	300 mA	300 mA	300 mA
		195															300 mA	300 mA	300 mA	300 mA
		196															300 mA	300 mA	300 mA	300 mA
		197															300 mA	300 mA	300 mA	300 mA
		198															300 mA	300 mA	300 mA	300 mA
hFE		199															350 mA	350 mA	350 mA	350 mA
		200															350 mA	350 mA	350 mA	350 mA
		201															350 mA	350 mA	350 mA	350 mA
		202															350 mA	350 mA	350 mA	350 mA
		203															350 mA	350 mA	350 mA	350 mA
		204	IB_1														350 mA	350 mA	350 mA	350 mA
		205	IB_2														IB_1 -OUT1	500		
		206															IB_2 -OUT2	"	"	"
		207															IB_3 -OUT3	"	"	"
		208															IB_4 -OUT4	"	"	"
		209															IB_5 -OUT5	"	"	"
		210															IB_6 -OUT6	"	"	"
																	IB_7 -OUT7	"	"	"

TABLE III. Group A inspection for device type 02 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation												Measured terminal	Min	Max	Unit	
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	
9 $T_A = +25^\circ C$	tpLH	Fig. 4	211	IN ₁	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	GND	COM	OUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁
			212	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	0V	"	"	"	"	"	"	"	OUT	IN ₁ -OUT ₁
			213									"	"	"	"	"	"	"	"	IN ₂ -OUT ₂
			214									"	"	"	"	"	"	"	"	IN ₃ -OUT ₃
			215									"	"	"	"	"	"	"	"	IN ₄ -OUT ₄
			216									"	"	"	"	"	"	"	"	IN ₅ -OUT ₅
			217									"	"	"	"	"	"	"	"	IN ₆ -OUT ₆
	tpHL	Fig. 4	218	IN ₁	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	"	"	"	"	"	"	"	"	IN ₇ -OUT ₇
			219									"	"	"	"	"	"	"	"	OUT
			220									"	"	"	"	"	"	"	"	OUT
			221									"	"	"	"	"	"	"	"	OUT
			222									"	"	"	"	"	"	"	"	OUT
			223									"	"	"	"	"	"	"	"	OUT
			224									"	"	"	"	"	"	"	"	OUT

NOTE: Pins not designated are open.

TABLE III. Group A inspection for device type 03.

Subgroup	Symbol	MIL-STD-883 Test no.	MIL-method	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit
				1	2	3	4	5	6	7	8	9	10	11	12	13	14				
1 $T_A = +25^\circ C$	I _{CEx}	1									0 V							OUT ₁	10.0 μA		
		2									"							OUT ₂	"		
		3									"							OUT ₃	"		
		4									"							OUT ₄	"		
		5									"							OUT ₅	"		
		6									"							OUT ₆	"		
		7									"							OUT ₇	"		
	V _{CE(sat)}	3007	8	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	350 mA	350 mA	350 mA	V
		9	10	11	12	13	14											OUT ₁	1.6		
																		OUT ₂	"		
V _{CE(sat)}	3007	15	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 mA	350 mA	350 mA	
		16	17	18	19	20	21											OUT ₃	"		
																		OUT ₄	"		
																		OUT ₅	"		
																		OUT ₆	"		
																		OUT ₇	"		
	V _{CE(sat)}	3007	22	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	200 mA	200 mA	200 mA	
		23	24	25	26	27	28											200 mA	200 mA	200 mA	
I _{IN(on)}	29	3.85 V	30	3.85 V	31	3.85 V	32	3.85 V	33	3.85 V	34	3.85 V	35					100 mA	100 mA	100 mA	
																		100 mA	100 mA	100 mA	
																		100 mA	100 mA	100 mA	
																		100 mA	100 mA	100 mA	
																		100 mA	100 mA	100 mA	
																		100 mA	100 mA	100 mA	
																		100 mA	100 mA	100 mA	
	I _{IN(off)}	36	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	50V	50V	50V	
		37	38	39	40	41	42											OUT ₁	500 μA		
																	OUT ₂	"			
																	OUT ₃	"			
																	OUT ₄	"			
																	OUT ₅	"			
																	OUT ₆	"			
																	OUT ₇	"			

TABLE III. Group A inspection for device type 03 – Continued.

Subgroup	Symbol	MIL-STD-883 Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit	
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16			
1 $T_A = +25^\circ C$	$V_{IN(on)}$	43	2.0 V							0 V							200 mA	OUT ₁	2.0 V		
		44	2.0 V							"							200 mA	OUT ₂	"	"	
		45								"							200 mA	OUT ₃	"	"	
		46								"							200 mA	OUT ₄	"	"	
		47								"							200 mA	OUT ₅	"	"	
		48								"							200 mA	OUT ₆	"	"	
		49								"							200 mA	OUT ₇	"	"	
	$V_{IN(on)}$	50	2.2 V							0 V							250 mA	OUT ₁	2.0 V		
		51	2.2 V							"							250 mA	OUT ₂	"	"	
		52								"							250 mA	OUT ₃	"	"	
$V_{IN(on)}$		53								"							250 mA	OUT ₄	"	"	
		54								"							250 mA	OUT ₅	"	"	
		55								"							250 mA	OUT ₆	"	"	
		56								"							250 mA	OUT ₇	"	"	
	$V_{IN(on)}$	57	2.4 V							0 V							300 mA	OUT ₁	2.0 V		
		58	2.4 V							"							300 mA	OUT ₂	"	"	
		59								"							300 mA	OUT ₃	"	"	
		60								"							300 mA	OUT ₄	"	"	
		61								"							300 mA	OUT ₅	"	"	
		62								"							300 mA	OUT ₆	"	"	
		63								"							300 mA	OUT ₇	"	"	
$ R $		64									50 V							0 V	COM	10.0 μA	
		65								"								COM	"	"	
		66								"								COM	"	"	
		67								"								COM	"	"	
		68								"								COM	"	"	
		69								"								COM	"	"	
		70								"								COM	"	"	
	V_F	71								0 V	0 V						350 mA	OUT ₁	2.0 V		
		72								"	"						350 mA	OUT ₂	"	"	
		73								"	"						350 mA	OUT ₃	"	"	
hFE		74								"	"						350 mA	OUT ₄	"	"	
		75								"	"						350 mA	OUT ₅	"	"	
		76								"	"						350 mA	OUT ₆	"	"	
		77								"	"						350 mA	OUT ₇	"	"	
		78	B ₁							"							350 mA	B ₁ -OUT ₁	1000		
		79	B ₂							"							350 mA	B ₂ -OUT ₂	"		
		80		B ₃						"							350 mA	B ₃ -OUT ₃	"		
		81		B ₄						"							350 mA	B ₄ -OUT ₄	"		
		82		B ₅						"							350 mA	B ₅ -OUT ₅	"		
		83		B ₆						"							350 mA	B ₆ -OUT ₆	"		
		84		B ₇						"							350 mA	B ₇ -OUT ₇	"		

TABLE III. Group A inspection for device type 03 – Continued.

Subgroup	Symbol	MIL-STD-883 Test no.	MIL-STD-method	Pin number and signal designation																Measured terminal	Limits Min	Limits Max	Unit
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16				
2 $T_A = +125^\circ C$	IcEX	85									0 V									OUT1	10.0 μA		
		86									"									OUT2	"		
		87									"									OUT3	"		
		88									"									OUT4	"		
		89									"									OUT5	"		
		90									"									OUT6	"		
		91									"									OUT7	"		
		3007	92	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 mA	350 mA	350 mA	V	
		93	94	95	96	97	98													OUT1	1.8		
		94	95	96	97	98														OUT2	"		
VCE(sat)	VCE(sat)	3007	99	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 mA	350 mA	350 mA	350 mA		
		100	101	102	103	104	105												200 mA	200 mA	200 mA	200 mA	
		101	102	103	104	105													200 mA	200 mA	200 mA	200 mA	
		102	103	104	105														200 mA	200 mA	200 mA	200 mA	
		103	104	105															200 mA	200 mA	200 mA	200 mA	
		104	105																200 mA	200 mA	200 mA	200 mA	
		105																	200 mA	200 mA	200 mA	200 mA	
		106	107	108	109	110	111	112											100 mA	100 mA	100 mA	100 mA	
		107	108	109	110	111	112												100 mA	100 mA	100 mA	100 mA	
		108	109	110	111	112													100 mA	100 mA	100 mA	100 mA	
IN(on)	IN(off)	113	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	50V	50V	50V	50V	
		114	115	116	117	118	119												OUT1	500 μA			
		115	116	117	118	119													OUT2	"			
		116	117	118	119														OUT3	"			
		117	118	119															OUT4	"			
		118	119																OUT5	"			
		119																	OUT6	"			
		120	121	122	123	124	125	126											OUT7	"			

TABLE III. Group A inspection for device type 03 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit
			IN ₁	2	3	4	5	6	7	8	9	10	11	12	13	14	15			
$T_A = +125^\circ C$	$V_{IN(on)}$	127	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	OUT ₁	2.0 V	u	
	$V_{IN(on)}$	128	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	200 mA	OUT ₂	u	
	$V_{IN(on)}$	129	u	u	u	u	u	u	u	u	u	u	u	u	u	u	200 mA	OUT ₃	u	
	$V_{IN(on)}$	130	u	u	u	u	u	u	u	u	u	u	u	u	u	u	200 mA	OUT ₄	u	
	$V_{IN(on)}$	131	u	u	u	u	u	u	u	u	u	u	u	u	u	u	200 mA	OUT ₅	u	
	$V_{IN(on)}$	132	u	u	u	u	u	u	u	u	u	u	u	u	u	u	200 mA	OUT ₆	u	
	$V_{IN(on)}$	133	u	u	u	u	u	u	u	u	u	u	u	u	u	u	200 mA	OUT ₇	u	
	$V_{IN(on)}$	134	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	250 mA	OUT ₁	2.0 V	u
	$V_{IN(on)}$	135	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	250 mA	OUT ₂	u	
	$V_{IN(on)}$	136	u	u	u	u	u	u	u	u	u	u	u	u	u	u	250 mA	OUT ₃	u	
V_F	I_R	137	u	u	u	u	u	u	u	u	u	u	u	u	u	u	250 mA	OUT ₄	u	
	I_R	138	u	u	u	u	u	u	u	u	u	u	u	u	u	u	250 mA	OUT ₅	u	
	I_R	139	u	u	u	u	u	u	u	u	u	u	u	u	u	u	250 mA	OUT ₆	u	
	I_R	140	u	u	u	u	u	u	u	u	u	u	u	u	u	u	250 mA	OUT ₇	u	
	V_F	141	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	0 V	0 V	0 V	
	V_F	142	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	0 V	0 V	0 V	
	V_F	143	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
	V_F	144	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
	V_F	145	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
	V_F	146	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
hFE	I_B	147	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
	I_B	148	u	u	u	u	u	u	u	u	u	u	u	u	u	u	50 V	50 V	50 V	
	I_B	149	u	u	u	u	u	u	u	u	u	u	u	u	u	u	100 mA	100 mA	100 mA	
	I_B	150	u	u	u	u	u	u	u	u	u	u	u	u	u	u	100 mA	100 mA	100 mA	
	I_B	151	u	u	u	u	u	u	u	u	u	u	u	u	u	u	100 mA	100 mA	100 mA	
	I_B	152	u	u	u	u	u	u	u	u	u	u	u	u	u	u	100 mA	100 mA	100 mA	
	I_B	153	u	u	u	u	u	u	u	u	u	u	u	u	u	u	100 mA	100 mA	100 mA	
	I_B	154	u	u	u	u	u	u	u	u	u	u	u	u	u	u	100 mA	100 mA	100 mA	
3003	I_B	155	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
	I_B	156	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
	I_B	157	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
	I_B	158	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
	I_B	159	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
	I_B	160	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
	I_B	161	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
	I_B	162	u	u	u	u	u	u	u	u	u	u	u	u	u	u	0 V	0 V	0 V	
3003	I_B	163	u	u	u	u	u	u	u	u	u	u	u	u	u	u	IB ₁ -OUT ₁	1000 mA	1000 mA	
	I_B	164	u	u	u	u	u	u	u	u	u	u	u	u	u	u	IB ₂ -OUT ₂	u	u	
	I_B	165	u	u	u	u	u	u	u	u	u	u	u	u	u	u	IB ₃ -OUT ₃	u	u	
	I_B	166	u	u	u	u	u	u	u	u	u	u	u	u	u	u	IB ₄ -OUT ₄	u	u	
	I_B	167	u	u	u	u	u	u	u	u	u	u	u	u	u	u	IB ₅ -OUT ₅	u	u	
	I_B	168	u	u	u	u	u	u	u	u	u	u	u	u	u	u	IB ₆ -OUT ₆	u	u	
	I_B	169	u	u	u	u	u	u	u	u	u	u	u	u	u	u	IB ₇ -OUT ₇	u	u	

TABLE III. Group A inspection for device type 03 – Continued.

Subgroup	Symbol	MIL-STD-883 Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit
			1	2	3	4	5	6	7	8	9	10	11	12	13	14				
3 $T_A = -55^\circ C$	IcEX	169							0 V								OUT ₁	10.0 μA		
		170							"								OUT ₂	"		
		171							"								OUT ₃	"		
		172							"								OUT ₄	"		
		173							"								OUT ₅	"		
		174							"								OUT ₆	"		
		175							"								OUT ₇	"		
		3007	176	850 μA	350 mA	350 mA	350 mA	V												
		177															OUT ₁	1.8		
		178															OUT ₂	"		
V _{CE(sat)}	V _{CE(sat)}	179															OUT ₃	"		
		180															OUT ₄	"		
		181															OUT ₅	"		
		182															OUT ₆	"		
		3007	183	550 μA	200 mA	200 mA	200 mA	V												
		184															OUT ₇	1.5		
		185															OUT ₁	"		
		186															OUT ₂	"		
		187															OUT ₃	"		
		188															OUT ₄	"		
V _{CE(sat)}	V _{CE(sat)}	189															OUT ₅	"		
		190	191	350 μA	200 mA	200 mA	200 mA	V												
		192															OUT ₆	"		
		193															OUT ₇	1.3		
		194															OUT ₁	"		
		195															OUT ₂	"		
		196															OUT ₃	"		
		197	198	3.85 V	100 mA	100 mA	100 mA	V												
		199															OUT ₄	"		
		200															OUT ₅	"		
I _{IN(on)}	I _{IN(off)}	201															OUT ₆	"		
		202															OUT ₇	"		
		203															IN ₁	650		
		204	205	25 μA	50V	50V	50V	μA												
		206															IN ₂	"		
		207															IN ₃	"		
		208															IN ₄	"		
		209															IN ₅	"		
		210															IN ₆	"		
																	IN ₇	"		

TABLE III. Group A inspection for device type 03 – Continued.

Subgroup	Symbol	MIL-STD-883 Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		
3 $T_A = -55^\circ C$	$V_{IN(on)}$	211 212 213 214 215 216 217	2.6 V 2.6 V 2.6 V 2.6 V 2.6 V 2.6 V 2.8 V	IN ₁ IN ₂ IN ₃ IN ₄ IN ₅ IN ₆ IN ₇	0 V “ “ “ “ “ 0 V	GND COM OUT ₇ OUT ₆ OUT ₅ OUT ₄ OUT ₃	0 V “ “ “ “ “ 2.6 V	200 mA 200 mA 200 mA 200 mA 200 mA 200 mA 2.6 V	200 mA 200 mA 200 mA 200 mA 200 mA 200 mA “	200 mA 200 mA 200 mA 200 mA 200 mA 200 mA “	200 mA 200 mA 200 mA 200 mA 200 mA 200 mA “	OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇	2.0 V “ “ “ “ “ “	2.0 V “ “ “ “ “ “	2.0 V “ “ “ “ “ “					
	$V_{IN(on)}$	218 219 220 221 222 223 224	2.8 V 2.8 V 2.8 V 2.8 V 2.8 V 2.8 V 2.8 V	“ “ “ “ “ “ “	0 V “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	250 mA 250 mA 250 mA 250 mA 250 mA 250 mA 250 mA	250 mA 250 mA 250 mA 250 mA 250 mA 250 mA 250 mA	OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇	2.0 V “ “ “ “ “ “	2.0 V “ “ “ “ “ “	2.0 V “ “ “ “ “ “				
	$V_{IN(on)}$	225 226 227 228 229 230 231	3.0 V 3.0 V 3.0 V 3.0 V 3.0 V 3.0 V 3.0 V	“ “ “ “ “ “ “	0 V “ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	300 mA 300 mA 300 mA 300 mA 300 mA 300 mA 300 mA	300 mA 300 mA 300 mA 300 mA 300 mA 300 mA 300 mA	OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇	2.0 V “ “ “ “ “ “	2.0 V “ “ “ “ “ “	2.0 V “ “ “ “ “ “				
	$ R $	232 233 234 235 236 237 238	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	0 V 0 V 0 V 0 V 0 V 0 V 0 V	0 V 0 V 0 V 0 V 0 V 0 V 0 V	COM COM COM COM COM COM COM	0 V 0 V 0 V 0 V 0 V 0 V 0 V	0 V 0 V 0 V 0 V 0 V 0 V 0 V	10.0 μA “ “ “ “ “ “				
	V_F	239 240 241 242 243 244 245	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇	2.0 V “ “ “ “ “ “	2.0 V “ “ “ “ “ “	2.0 V “ “ “ “ “ “				
	hFE	3003 246 247 248 249 250 251 252	IB ₁ IB ₂ IB ₃ IB ₄ IB ₅ IB ₆ IB ₇	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	IB ₁ -OUT ₁ IB ₂ -OUT ₂ IB ₃ -OUT ₃ IB ₄ -OUT ₄ IB ₅ -OUT ₅ IB ₆ -OUT ₆ IB ₇ -OUT ₇	500 “ “ “ “ “ “ “	500 “ “ “ “ “ “ “	500 “ “ “ “ “ “ “				

TABLE III. Group A inspection for device type 03 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation														Measured terminal	Limits	Unit	
				1	2	3	4	5	6	7	8	9	10	11	12	13	14				
9 $T_A = +25^\circ C$	t_{PLH} Fig. 4	253	IN_1	IN_2	IN_3	IN_4	IN_5	IN_6	IN_7	GND	COM	OUT_7	OUT_6	OUT_5	OUT_4	OUT_3	OUT_2	OUT_1	IN_1-OUT_1	750	ns
		254								0V								OUT	IN_2-OUT_2	"	"
		255								"								OUT	IN_3-OUT_3	"	"
		256								"								OUT	IN_4-OUT_4	"	"
		257								"								OUT	IN_5-OUT_5	"	"
	t_{PHL} Fig. 4	258								"								OUT	IN_6-OUT_6	"	"
		259								"								OUT	IN_7-OUT_7	"	"
		260	IN_1	IN_2	IN_3	IN_4	IN_5	IN_6	IN_7	"								OUT	IN_1-OUT_1	300	ns
		261								"								OUT	IN_2-OUT_2	"	"
		262								"								OUT	IN_3-OUT_3	"	"
		263								"								OUT	IN_4-OUT_4	"	"
		264								"								OUT	IN_5-OUT_5	"	"
		265								"								OUT	IN_6-OUT_6	"	"
		266								"								OUT	IN_7-OUT_7	"	"

NOTE: Pins not designated are open.

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TABLE III. Group A inspection for device type 04.

TABLE III. Group A inspection for device type 04 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit
				IN ₁	2	3	4	5	6	7	8	9	10	11	12	13	14				
$T_A = +25^\circ C$	$I_{IN(off)}$	43	25 μA	44	25 μA	45	25 μA	46	25 μA	47	25 μA	48	25 μA	49	25 μA	50	0 V	OUT ₁	500 μA		
	$V_{IN(on)}$	51	5.0 V	52	5.0 V	53	5.0 V	54	5.0 V	55	5.0 V	56	5.0 V	57	6.0 V	58	6.0 V	59	6.0 V	OUT ₂	4 u
	$V_{IN(on)}$	60	6.0 V	61	6.0 V	62	6.0 V	63	6.0 V	64	7.0 V	65	7.0 V	66	7.0 V	67	7.0 V	68	7.0 V	OUT ₃	4 u
	$V_{IN(on)}$	69	7.0 V	70	7.0 V	71	8.0 V	72	8.0 V	73	8.0 V	74	8.0 V	75	8.0 V	76	8.0 V	77	8.0 V	OUT ₄	4 u
	I_R	78		79		80		81		82		83		84					COM	10.0 μA	
	$V_{IN(on)}$	85	8.0 V	86	8.0 V	87	8.0 V	88	8.0 V	89	8.0 V	90	8.0 V	91	8.0 V	92	8.0 V	93	8.0 V	OUT ₅	4 u
	$V_{IN(on)}$	94	8.0 V	95	8.0 V	96	8.0 V	97	8.0 V	98	8.0 V	99	8.0 V	100	8.0 V	101	8.0 V	102	8.0 V	OUT ₆	4 u
	$V_{IN(on)}$	103	8.0 V	104	8.0 V	105	8.0 V	106	8.0 V	107	8.0 V	108	8.0 V	109	8.0 V	110	8.0 V	111	8.0 V	OUT ₇	4 u
	$V_{IN(on)}$	112	8.0 V	113	8.0 V	114	8.0 V	115	8.0 V	116	8.0 V	117	8.0 V	118	8.0 V	119	8.0 V	120	8.0 V	OUT ₁	500 V
	$V_{IN(on)}$	121	8.0 V	122	8.0 V	123	8.0 V	124	8.0 V	125	8.0 V	126	8.0 V	127	8.0 V	128	8.0 V	129	8.0 V	OUT ₂	4 u
	$V_{IN(on)}$	130	8.0 V	131	8.0 V	132	8.0 V	133	8.0 V	134	8.0 V	135	8.0 V	136	8.0 V	137	8.0 V	138	8.0 V	OUT ₃	4 u
	$V_{IN(on)}$	139	8.0 V	140	8.0 V	141	8.0 V	142	8.0 V	143	8.0 V	144	8.0 V	145	8.0 V	146	8.0 V	147	8.0 V	OUT ₄	4 u
	$V_{IN(on)}$	148	8.0 V	149	8.0 V	150	8.0 V	151	8.0 V	152	8.0 V	153	8.0 V	154	8.0 V	155	8.0 V	156	8.0 V	OUT ₅	4 u
	$V_{IN(on)}$	157	8.0 V	158	8.0 V	159	8.0 V	160	8.0 V	161	8.0 V	162	8.0 V	163	8.0 V	164	8.0 V	165	8.0 V	OUT ₆	4 u
	$V_{IN(on)}$	166	8.0 V	167	8.0 V	168	8.0 V	169	8.0 V	170	8.0 V	171	8.0 V	172	8.0 V	173	8.0 V	174	8.0 V	OUT ₇	4 u
	$V_{IN(on)}$	175	8.0 V	176	8.0 V	177	8.0 V	178	8.0 V	179	8.0 V	180	8.0 V	181	8.0 V	182	8.0 V	183	8.0 V	OUT ₁	2.0 V
	$V_{IN(on)}$	184	8.0 V	185	8.0 V	186	8.0 V	187	8.0 V	188	8.0 V	189	8.0 V	190	8.0 V	191	8.0 V	192	8.0 V	OUT ₂	4 u
	$V_{IN(on)}$	193	8.0 V	194	8.0 V	195	8.0 V	196	8.0 V	197	8.0 V	198	8.0 V	199	8.0 V	200	8.0 V	201	8.0 V	OUT ₃	4 u
	$V_{IN(on)}$	202	8.0 V	203	8.0 V	204	8.0 V	205	8.0 V	206	8.0 V	207	8.0 V	208	8.0 V	209	8.0 V	210	8.0 V	OUT ₄	4 u
	$V_{IN(on)}$	211	8.0 V	212	8.0 V	213	8.0 V	214	8.0 V	215	8.0 V	216	8.0 V	217	8.0 V	218	8.0 V	219	8.0 V	OUT ₅	4 u
	$V_{IN(on)}$	220	8.0 V	221	8.0 V	222	8.0 V	223	8.0 V	224	8.0 V	225	8.0 V	226	8.0 V	227	8.0 V	228	8.0 V	OUT ₆	4 u
	$V_{IN(on)}$	229	8.0 V	230	8.0 V	231	8.0 V	232	8.0 V	233	8.0 V	234	8.0 V	235	8.0 V	236	8.0 V	237	8.0 V	OUT ₇	4 u

TABLE III. Group A inspection for device type 04 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation																Measured terminal	Limits	Min	Max	Unit
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16					
1 $T_A = +25^\circ\text{C}$	V_F		85	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	GND	COM	OUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	OUT ₁	2.0	V		
			86								0 V	0 V								OUT ₂	OUT ₄	"	"	
			87								"	"								OUT ₃	OUT ₅	"	"	
			88								"	"								OUT ₄	OUT ₆	"	"	
			89								"	"								OUT ₅	OUT ₇	"	"	
	hFE		90	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	0 V	0 V								OUT ₆	OUT ₇	"	"	
			91	IB ₁	IB ₂	IB ₃	IB ₄	IB ₅	IB ₆	IB ₇	"	"								OUT ₁	OUT ₂	2.0	V	
			92	IB ₁	IB ₂	IB ₃	IB ₄	IB ₅	IB ₆	IB ₇	"	"								OUT ₃	OUT ₅	"	"	
			93								"	"								OUT ₄	OUT ₆	"	"	
			94								"	"								OUT ₅	OUT ₇	"	"	
2 $T_A = +125^\circ\text{C}$	I_{CEX}		95	IB ₁	IB ₂	IB ₃	IB ₄	IB ₅	IB ₆	IB ₇	0 V	"								OUT ₁	OUT ₂	10.0	μA	
			96								"	"								OUT ₃	OUT ₄	"	"	
			97								"	"								OUT ₅	OUT ₆	"	"	
			98								"	"								OUT ₇	OUT ₇	"	"	
			99								"	"								OUT ₁	OUT ₂	10.0	μA	
	$V_{CE(\text{sat})}$		100								"	"								OUT ₃	OUT ₄	"	"	
			101								"	"								OUT ₅	OUT ₆	"	"	
			102								"	"								OUT ₇	OUT ₇	"	"	
			103								"	"								OUT ₁	OUT ₂	1.8	V	
			104								"	"								OUT ₃	OUT ₄	"	"	
			105								"	"								OUT ₅	OUT ₆	"	"	
			106	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	
			107																	OUT ₇	OUT ₇	"	"	
			108																	OUT ₁	OUT ₂	1.8	V	
			109																	OUT ₃	OUT ₄	"	"	
			110																	OUT ₅	OUT ₆	"	"	
	$V_{CE(\text{sat})}$		111	112	113	114	115	116	117	118	119	350 μA												
			120	121	122	123	124	125	126			250 μA												
			121																	OUT ₁	OUT ₂	1.3	V	
			122																	OUT ₃	OUT ₄	"	"	
			123																	OUT ₅	OUT ₆	"	"	

TABLE III. Group A inspection for device type 04 - Continued.

Subgroup	Symbol	MIL-STD-883 Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit
			1	2	3	4	5	6	7	8	9	10	11	12	13	14				
$T_A = +125^\circ\text{C}$	$I_{IN(on)}$	127	5.0 V	5.0 V					0 V	"							IN1	250	500	μA
		128							"								IN2	"	"	"
		129							"								IN3	"	"	"
		130							"								IN4	"	"	"
		131							"								IN5	"	"	"
		132							"								IN6	"	"	"
	$I_{IN(on)}$	133															IN7	"	"	"
		134	12.0 V	12.0 V					"								IN1	750	1450	μA
		135							"								IN2	"	"	"
		136							"								IN3	"	"	"
		137							"								IN4	"	"	"
		138							"								IN5	"	"	"
		139							"								IN6	"	"	"
		140							"								IN7	"	"	"
	$I_{IN(off)}$	141	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	0 V	50 V	50 V	500 μA	
		142															OUT1	"	"	"
		143															OUT2	"	"	"
		144															OUT3	"	"	"
		145															OUT4	"	"	"
		146															OUT5	"	"	"
		147															OUT6	"	"	"
	$V_{IN(on)}$	148	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	0 V	125 mA	125 mA	125 mA	2.0 V
		149															OUT1	"	"	"
		150															OUT2	"	"	"
		151															OUT3	"	"	"
		152															OUT4	"	"	"
		153															OUT5	"	"	"
		154															OUT6	"	"	"
		155	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	0 V	200 mA	200 mA	200 mA	2.0 V
		156															OUT7	"	"	"
		157															OUT1	"	"	"
		158															OUT2	"	"	"
		159															OUT3	"	"	"
		160															OUT4	"	"	"
		161															OUT5	"	"	"
		162	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	0 V	275 mA	275 mA	275 mA	2.0 V
		163															OUT6	"	"	"
		164															OUT7	"	"	"
		165															OUT1	"	"	"
		166															OUT2	"	"	"
		167															OUT3	"	"	"
		168															OUT4	"	"	"
																	OUT5	"	"	"
																	OUT6	"	"	"
																	OUT7	"	"	"

TABLE III. Group A inspection for device type 04 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit						
				1	2	3	4	5	6	7	8	9	10	11	12	13	14										
2 $T_A = +125^\circ C$	$V_{IN(on)}$		169 170 171 172 173 174 175	8.0 V 8.0 V 8.0 V 8.0 V 8.0 V 8.0 V	8.0 V 8.0 V 8.0 V 8.0 V 8.0 V 8.0 V	0 V u u u u u	GND IN6 IN5 IN4 IN3 IN2 IN1	COM OUT7 OUT6 OUT5 OUT4 OUT3 OUT2	OUT5 OUT4 OUT3 OUT2 OUT1	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	OUT1 OUT2 OUT3 OUT4 OUT5 OUT6 OUT7	OUT1 OUT2 OUT3 OUT4 OUT5 OUT6 OUT7	2.0 u u u u u u	V u u u u u u													
	$ R $		176 177 178 179 180 181 182														0 V 0 V 0 V 0 V 0 V 0 V 0 V	0 V 0 V 0 V 0 V 0 V 0 V 0 V	0 V 0 V 0 V 0 V 0 V 0 V 0 V	0 V 0 V 0 V 0 V 0 V 0 V 0 V	0 V 0 V 0 V 0 V 0 V 0 V 0 V	COM COM COM COM COM COM COM	COM COM COM COM COM COM COM	10.0 u u u u u u	μA u u u u u u		
	V_F		183 184 185 186 187 188 189														0 V 0 V 0 V 0 V 0 V 0 V 0 V	0 V 0 V 0 V 0 V 0 V 0 V 0 V	0 V 0 V 0 V 0 V 0 V 0 V 0 V	0 V 0 V 0 V 0 V 0 V 0 V 0 V	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	OUT1 OUT2 OUT3 OUT4 OUT5 OUT6 OUT7	OUT1 OUT2 OUT3 OUT4 OUT5 OUT6 OUT7	2.0 u u u u u u	V u u u u u u
	hFE		190 191 192 193 194 195 196	IB_1 IB_2 IB_3 IB_4 IB_5 IB_6 IB_7													350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	IB1-OUT1 IB2-OUT2 IB3-OUT3 IB4-OUT4 IB5-OUT5 IB6-OUT6 IB7-OUT7	IB1-OUT1 IB2-OUT2 IB3-OUT3 IB4-OUT4 IB5-OUT5 IB6-OUT6 IB7-OUT7	1000 u u u u u u				
	I_{CEX}		197 198 199 200 201 202 203														50 V 50 V 50 V 50 V 50 V 50 V 50 V	50 V 50 V 50 V 50 V 50 V 50 V 50 V	50 V 50 V 50 V 50 V 50 V 50 V 50 V	50 V 50 V 50 V 50 V 50 V 50 V 50 V	OUT1 OUT2 OUT3 OUT4 OUT5 OUT6 OUT7	OUT1 OUT2 OUT3 OUT4 OUT5 OUT6 OUT7	10.0 u u u u u u	μA u u u u u u			
	$V_{CE(sat)}$		204 205 206 207 208 209 210	$850 \mu A$ $850 \mu A$ $850 \mu A$ $850 \mu A$ $850 \mu A$ $850 \mu A$ $850 \mu A$												350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	350 mA 350 mA 350 mA 350 mA 350 mA 350 mA 350 mA	OUT1 OUT2 OUT3 OUT4 OUT5 OUT6 OUT7	OUT1 OUT2 OUT3 OUT4 OUT5 OUT6 OUT7	1.8 u u u u u u u	V u u u u u u				

TABLE III. Group A inspection for device type 04 - Continued.

Subgroup	Symbol	MIL-STD-883	Test no.	Pin number and signal designation																Measured terminal	Limits Min	Limits Max	Unit
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16				
3 $T_A = -55^\circ C$	$V_{CE}(\text{sat})$	3007	211	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₁	1.5 V	u	
			212	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₂	u	u	
		213									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₃	u	u	
		214									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₄	u	u	
		215									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₅	u	u	
		216									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₆	u	u	
		217									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₇	u	u	
	$V_{CE}(\text{sat})$	3007	218	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	IN ₁	1.3 V	V	
			219	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	IN ₂	u	u	
		220									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₃	u	u	
		221									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₄	u	u	
		222									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₅	u	u	
		223									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₆	u	u	
		224									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₇	u	u	
4 $I_{IN(on)}$	$I_{IN(on)}$	225	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	IN ₁	250 μA	μA	
			226	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	IN ₂	u	u	
		227									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₃	u	u	
		228									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₄	u	u	
		229									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₅	u	u	
		230									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₆	u	u	
		231									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₇	u	u	
		232	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	IN ₁	750 μA	μA	
		233									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₂	u	u	
		234									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₃	u	u	
		235									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₄	u	u	
		236									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₅	u	u	
		237									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₆	u	u	
		238									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	IN ₇	u	u	
5 $I_{IN(off)}$	$I_{IN(off)}$	239	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	50 V	50 V	μA		
			240	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	50 V	50 V	μA		
		241									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₁	500 μA	μA	
		242									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₂	u	u	
		243									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₃	u	u	
		244									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₄	u	u	
		245									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₅	u	u	
		246	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	OUT ₆	125 mA	mA	
		247									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₇	u	u	
		248									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₁	2.0 V	V	
		249									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₂	u	u	
		250									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₃	u	u	
		251									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₄	u	u	
		252									0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	OUT ₅	u	u	
																			OUT ₆	u	u		
																			OUT ₇	u	u		

TABLE III. Group A inspection for device type 04 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit
				IN ₁	2	3	4	5	6	7	8	9	10	11	12	13	14				
3 $T_A = -55^\circ C$	$V_{IN(on)}$	253	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	0 V	0 V	200 mA	200 mA	OUT ₁	200 mA	2.0 V		
		254	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA	OUT ₂	"	"	
		255	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA	OUT ₃	"	"	
		256	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA	OUT ₄	"	"	
		257	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA	OUT ₅	"	"	
		258	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA	OUT ₆	"	"	
		259	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA	OUT ₇	"	"	
	$V_{IN(on)}$	260	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	0 V	0 V	275 mA	275 mA	OUT ₁	275 mA	2.0 V		
		261	"	"	"	"	"	"	"	"	"	"	"	"	"	275 mA	275 mA	OUT ₂	"	"	
		262	"	"	"	"	"	"	"	"	"	"	"	"	"	275 mA	275 mA	OUT ₃	"	"	
$V_{IN(on)}$		263	"	"	"	"	"	"	"	"	"	"	"	"	"	275 mA	275 mA	OUT ₄	"	"	
		264	"	"	"	"	"	"	"	"	"	"	"	"	"	275 mA	275 mA	OUT ₅	"	"	
		265	"	"	"	"	"	"	"	"	"	"	"	"	"	275 mA	275 mA	OUT ₆	"	"	
		266	"	"	"	"	"	"	"	"	"	"	"	"	"	275 mA	275 mA	OUT ₇	"	"	
		267	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	0 V	0 V	350 mA	350 mA	OUT ₁	350 mA	2.0 V		
		268	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	OUT ₂	"	"	
		269	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	OUT ₃	"	"	
		270	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	OUT ₄	"	"	
		271	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	OUT ₅	"	"	
		272	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	OUT ₆	"	"	
I_R		273	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	OUT ₇	"	"	
		274	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	10.0 μ A	"	"	
		275	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
		276	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
		277	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
		278	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
		279	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
		280	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
		281	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
		282	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
V_F		283	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
		284	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
		285	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
		286	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
		287	"	"	"	"	"	"	"	"	"	"	"	"	"	50 V	50 V	COM	50 V	"	
		288	IB ₁	IB ₂	IB ₃	IB ₄	IB ₅	IB ₆	IB ₇	"	"	"	"	"	"	350 mA	350 mA	IB ₁ -OUT ₁	500	"	
		289	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	IB ₂ -OUT ₂	"	"	
		290	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	IB ₃ -OUT ₃	"	"	
		291	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	IB ₄ -OUT ₄	"	"	
		292	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	IB ₅ -OUT ₅	"	"	
hFE		293	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	IB ₆ -OUT ₆	"	"	
		294	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	IB ₇ -OUT ₇	"	"	

TABLE III. Group A inspection for device type 04 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation														Measured terminal	Limits	Unit			
				1	2	3	4	5	6	7	8	9	10	11	12	13	14						
9 $T_A = +25^\circ C$	t_{PLH} Fig. 4	3003	295	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	0 V	GND	COM	OUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	750	ns	
		296	297		IN ₂														OUT	OUT	IN ₁ -OUT ₁	"	"
		298	299			IN ₃													OUT	OUT	IN ₂ -OUT ₂	"	"
		300	301				IN ₄											OUT	OUT	IN ₃ -OUT ₃	"	"	
		302	303	IN ₁	IN ₂													OUT	OUT	IN ₄ -OUT ₄	"	"	
	t_{PHL} Fig. 4	3003	304			IN ₃												OUT	OUT	IN ₅ -OUT ₅	"	"	
		305	306				IN ₄											OUT	OUT	IN ₆ -OUT ₆	"	"	
		307	308					IN ₅										OUT	OUT	IN ₇ -OUT ₇	"	"	
									IN ₆														
										IN ₇													

NOTE: Pins not designated are open.

TABLE III. Group A inspection for device type 05.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit
				1	2	3	4	5	6	7	8	9	10	11	12	13	14				
1 $T_A = +25^\circ C$	IcEX	$I_{CE(sat)} = 3007$	1															OUT1	10.0 μA		
			2															OUT2	"	"	
			3															OUT3	"	"	
			4															OUT4	"	"	
			5															OUT5	"	"	
			6															OUT6	"	"	
			7															OUT7	"	"	
			8	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	50 V	50 V	50 V	
			9															50 V	50 V	50 V	
			10															350 mA	350 mA	350 mA	
			11															350 mA	350 mA	350 mA	
			12															350 mA	350 mA	350 mA	
			13															350 mA	350 mA	350 mA	
			14															350 mA	350 mA	350 mA	
			15	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	
V _{CE(sat)}	IcEX	$I_{CE(sat)} = 3007$	16															200 mA	200 mA	200 mA	
			17															200 mA	200 mA	200 mA	
			18															200 mA	200 mA	200 mA	
			19															200 mA	200 mA	200 mA	
			20															200 mA	200 mA	200 mA	
			21															200 mA	200 mA	200 mA	
			22	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	
			23															100 mA	100 mA	100 mA	
			24															100 mA	100 mA	100 mA	
			25															100 mA	100 mA	100 mA	
			26															100 mA	100 mA	100 mA	
			27															100 mA	100 mA	100 mA	
			28															100 mA	100 mA	100 mA	
			29	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	
I _{IN(on)}	IcEX	$I_{CE(sat)} = 3007$	30															IN1	1180 μA	2400 μA	
			31															IN2	"	"	
			32															IN3	"	"	
			33															IN4	"	"	
			34															IN5	"	"	
			35															IN6	"	"	
			36	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	
			37															OUT1	10.0 μA	500 μA	
			38															OUT2	"	"	
			39															OUT3	"	"	
			40															OUT4	"	"	
			41															OUT5	"	"	
			42															OUT6	"	"	
																		OUT7	"	"	

TABLE III. Group A inspection for device type_05 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation																Measured terminal	Limits Min	Limits Max	Unit
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16				
1 $T_A = +25^\circ C$	$V_{IN(on)}$		43	2.4 V	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	GND	COM	OUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	OUT ₁ terminal	2.0	V	
			44	2.4 V							0 V								350 mA	350 mA	OUT ₂	u	u
			45	2.4 V	2.4 V						u								350 mA	350 mA	OUT ₃	u	u
			46		2.4 V						u								350 mA	350 mA	OUT ₄	u	u
			47		2.4 V						u								350 mA	350 mA	OUT ₅	u	u
			48		2.4 V						u								350 mA	350 mA	OUT ₆	u	u
			49		2.4 V						u								350 mA	350 mA	OUT ₇	u	u
	I_R		50								50 V								0 V	0 V	COM	10.0	μA
			51								u								0 V	0 V	COM	u	u
2 $T_A = +125^\circ C$			52								u								0 V	0 V	COM	u	u
			53								u								0 V	0 V	COM	u	u
			54								u								0 V	0 V	COM	u	u
			55								u								0 V	0 V	COM	u	u
			56								u								0 V	0 V	COM	u	u
	V_F		57								0 V	0 V							350 mA	350 mA	OUT ₁	2.0	V
			58								u	u							350 mA	350 mA	OUT ₂	u	u
			59								u	u							350 mA	350 mA	OUT ₃	u	u
			60								u	u							350 mA	350 mA	OUT ₄	u	u
			61								u	u							350 mA	350 mA	OUT ₅	u	u
hFE			62								u	u							350 mA	350 mA	OUT ₆	u	u
			63								u	u							350 mA	350 mA	OUT ₇	u	u
			64	IB ₁							u								350 mA	350 mA	IB ₁ -OUT ₁	1000	
			65	IB ₂							u								350 mA	350 mA	IB ₂ -OUT ₂	“	
			66	IB ₃							u								350 mA	350 mA	IB ₃ -OUT ₃	“	
			67	IB ₄							u								350 mA	350 mA	IB ₄ -OUT ₄	“	
			68	IB ₅							u								350 mA	350 mA	IB ₅ -OUT ₅	“	
			69	IB ₆							u								350 mA	350 mA	IB ₆ -OUT ₆	“	
			70	IB ₇							u								350 mA	350 mA	IB ₇ -OUT ₇	“	
VCE(eat)			71								0 V								50 V	50 V	OUT ₁	10.0	μA
			72								u								50 V	50 V	OUT ₂	u	u
			73								u								50 V	50 V	OUT ₃	u	u
			74								u								50 V	50 V	OUT ₄	u	u
			75								u								50 V	50 V	OUT ₅	u	u
			76								u								50 V	50 V	OUT ₆	u	u
			77								u								50 V	50 V	OUT ₇	u	u
			78	500 μA							u								350 mA	350 mA	OUT ₁	1.8	V
			79	500 μA	500 μA						u								350 mA	350 mA	OUT ₂	u	u
			80	500 μA	500 μA						u								350 mA	350 mA	OUT ₃	u	u
			81	500 μA	500 μA						u								350 mA	350 mA	OUT ₄	u	u
			82	500 μA	500 μA						u								350 mA	350 mA	OUT ₅	u	u
			83	500 μA	500 μA						u								350 mA	350 mA	OUT ₆	u	u
			84	500 μA	500 μA						u								350 mA	350 mA	OUT ₇	u	u

TABLE III. Group A inspection for device type_05 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation														Measured		Limits	
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	terminal	Min
2 $T_A = +125^\circ C$	V _{CE(sat)}	3007	85 86 87 88 89 90 91	350 μA 350 μA 350 μA 350 μA 350 μA 250 μA 250 μA	IN ₁ IN ₂ IN ₃ IN ₄ IN ₅ IN ₆ IN ₇	0 V “ “ “ “ “ “ “	GND COM OUT ₇ OUT ₆ OUT ₅ OUT ₄ OUT ₃ OUT ₂	0 V “ “ “ “ “ “ “	200 mA 200 mA 200 mA 200 mA 200 mA 100 mA 100 mA 100 mA	200 mA 200 mA 200 mA 200 mA 200 mA 100 mA 100 mA 100 mA	OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇	200 mA 200 mA 200 mA 200 mA 200 mA 100 mA 100 mA 100 mA	OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇	1.5 “ “ “ “ “ “ “	V “ “ “ “ “ “ “					
	V _{CE(sat)}	3007	92 93 94 95 96 97 98	250 μA 250 μA 250 μA 250 μA 250 μA 250 μA 250 μA	250 μA 250 μA 250 μA 250 μA 250 μA 250 μA 250 μA	350 μA 350 μA 350 μA 350 μA 350 μA 350 μA 350 μA	350 μA 350 μA 350 μA 350 μA 350 μA 350 μA 350 μA	“ “ “ “ “ “ “	100 mA 100 mA 100 mA 100 mA 100 mA 100 mA 100 mA	100 mA 100 mA 100 mA 100 mA 100 mA 100 mA 100 mA	IN ₁ IN ₂ IN ₃ IN ₄ IN ₅ IN ₆ IN ₇	100 mA 100 mA 100 mA 100 mA 100 mA 100 mA 100 mA	1.3 “ “ “ “ “ “	V “ “ “ “ “ “						
	I _{IN(on)}	99 100 101 102 103 104 105	3.0 V 3.0 V 3.0 V 3.0 V 3.0 V 3.0 V 3.0 V	3.0 V 3.0 V 3.0 V 3.0 V 3.0 V 3.0 V 3.0 V	3.0 V 3.0 V 3.0 V 3.0 V 3.0 V 3.0 V 3.0 V	3.0 V 3.0 V 3.0 V 3.0 V 3.0 V 3.0 V 3.0 V	3.0 V 3.0 V 3.0 V 3.0 V 3.0 V 3.0 V 3.0 V	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	1180 “ “ “ “ “ “	2400 “ “ “ “ “ “	μA “ “ “ “ “ “			
	I _{IN(off)}	106 107 108 109 110 111 112	25 μA 25 μA 25 μA 25 μA 25 μA 25 μA 25 μA	25 μA 25 μA 25 μA 25 μA 25 μA 25 μA 25 μA	25 μA 25 μA 25 μA 25 μA 25 μA 25 μA 25 μA	25 μA 25 μA 25 μA 25 μA 25 μA 25 μA 25 μA	25 μA 25 μA 25 μA 25 μA 25 μA 25 μA 25 μA	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	500 “ “ “ “ “ “	μA “ “ “ “ “ “
	V _{IN(on)}	113 114 115 116 117 118 119	2.4 V 2.4 V 2.4 V 2.4 V 2.4 V 2.4 V 2.4 V	2.4 V 2.4 V 2.4 V 2.4 V 2.4 V 2.4 V 2.4 V	2.4 V 2.4 V 2.4 V 2.4 V 2.4 V 2.4 V 2.4 V	2.4 V 2.4 V 2.4 V 2.4 V 2.4 V 2.4 V 2.4 V	2.4 V 2.4 V 2.4 V 2.4 V 2.4 V 2.4 V 2.4 V	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	2.0 “ “ “ “ “ “	V “ “ “ “ “ “	
	I _R	120 121 122 123 124 125 126	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	“ “ “ “ “ “ “	10.0 “ “ “ “ “ “	μA “ “ “ “ “ “		

TABLE III. Group A inspection for device type_05 – Continued.

Subgroup	Symbol	MIL-STD-883 Test no.	Pin number and signal designation														Measured terminal	Limits Min	Limits Max	Unit
			1	2	3	4	5	6	7	8	9	10	11	12	13	14				
2 $T_A = +125^\circ C$	V_F	127								0 V	0 V					350 mA	OUT ₁	2.0	V	
		128								"	"					350 mA	OUT ₂	"	"	
		129								"	"					350 mA	OUT ₃	"	"	
		130								"	"					350 mA	OUT ₄	"	"	
		131								"	"					350 mA	OUT ₅	"	"	
		132								"	"					350 mA	OUT ₆	"	"	
		133								"	"					350 mA	OUT ₇	"	"	
	hFE	3003	IB ₁	IB ₂	IB ₃	IB ₄	IB ₅	IB ₆	IB ₇	0 V	0 V					350 mA	IB ₁ -OUT ₁	1000		
		135								"	"					350 mA	IB ₂ -OUT ₂	"		
		136								"	"					350 mA	IB ₃ -OUT ₃	"		
3 $T_A = -55^\circ C$		137								"	"					350 mA	IB ₄ -OUT ₄	"		
		138								"	"					350 mA	IB ₅ -OUT ₅	"		
		139								"	"					350 mA	IB ₆ -OUT ₆	"		
		140								"	"					350 mA	IB ₇ -OUT ₇	"		
	I_{CEX}	141														50 V	OUT ₁	10.0	μA	
		142														50 V	OUT ₂	"	"	
		143														50 V	OUT ₃	"	"	
		144														50 V	OUT ₄	"	"	
		145														50 V	OUT ₅	"	"	
		146														50 V	OUT ₆	"	"	
		147														50 V	OUT ₇	"	"	
$V_{CE(sat)}$	3007	148	850 μA							"	"					350 mA	OUT ₁	1.8	V	
		149	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	"	"					350 mA	OUT ₂	"	"	
		150								"	"					350 mA	OUT ₃	"	"	
		151								"	"					350 mA	OUT ₄	"	"	
		152								"	"					350 mA	OUT ₅	"	"	
		153								"	"					350 mA	OUT ₆	"	"	
		154								"	"					350 mA	OUT ₇	"	"	
		155	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	"	"					200 mA	OUT ₁	1.5	V	
		156								"	"					200 mA	OUT ₂	"	"	
		157								"	"					200 mA	OUT ₃	"	"	
$V_{CE(sat)}$	3007	158								"	"					200 mA	OUT ₄	"	"	
		159								"	"					200 mA	OUT ₅	"	"	
		160								"	"					200 mA	OUT ₆	"	"	
		161								"	"					200 mA	OUT ₇	"	"	
		162	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	"	"					100 mA	OUT ₁	1.3	V	
		163								"	"					100 mA	OUT ₂	"	"	
		164								"	"					100 mA	OUT ₃	"	"	
		165								"	"					100 mA	OUT ₄	"	"	
		166								"	"					100 mA	OUT ₅	"	"	
		167								"	"					100 mA	OUT ₆	"	"	
		168								"	"					100 mA	OUT ₇	"	"	

TABLE III. Group A inspection for device type_05 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation														Measured		Limits			
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	terminal	Min	Max
3 $T_A = -55^\circ C$	$I_{IN(on)}$	169	3.0 V	3.0 V	I_{N3}	I_{N4}	I_{N5}	I_{N6}	I_{N7}	GND	COM	OUT_7	OUT_6	OUT_5	OUT_4	OUT_3	OUT_2	OUT_1	IN1	1180	2400	μA
		170								0 V									IN2	"	"	"
		171								"									IN3	"	"	"
		172								"									IN4	"	"	"
		173								"									IN5	"	"	"
		174								"									IN6	"	"	"
		175								"									IN7	"	"	"
	$I_{IN(off)}$	176	25 μA	25 μA														50 V	50 V	OUT1	500	μA
		177																	OUT2	"	"	"
		178																	OUT3	"	"	"
$V_{IN(on)}$		179																	OUT4	"	"	"
		180																	OUT5	"	"	"
		181																	OUT6	"	"	"
		182																	OUT7	"	"	"
		183	3.0 V	3.0 V							0 V							350 mA	350 mA	OUT1	2.0	V
		184									"								OUT2	"	"	"
		185									"								OUT3	"	"	"
		186									"								OUT4	"	"	"
		187									"								OUT5	"	"	"
		188									"								OUT6	"	"	"
		189									"								OUT7	"	"	"
I_R		190															0 V	0 V	COM	10.0	μA	
		191																COM	COM	"	"	
		192																COM	COM	"	"	
		193																COM	COM	"	"	
		194																COM	COM	"	"	
		195																COM	COM	"	"	
		196																COM	COM	"	"	
V_F		197										0 V	0 V					350 mA	350 mA	OUT1	2.0	V
		198										"	"					OUT2	"	"	"	
		199										"	"					OUT3	"	"	"	
		200										"	"					OUT4	"	"	"	
		201										"	"					OUT5	"	"	"	
		202										"	"					OUT6	"	"	"	
		203										"	"					OUT7	"	"	"	
h_{FE}		204	I_{B1}														350 mA	350 mA	$I_{B1-OUT1}$	500		
		205	I_{B2}															$I_{B2-OUT2}$	"	"	"	
		206																$I_{B3-OUT3}$	"	"	"	
		207																$I_{B4-OUT4}$	"	"	"	
		208																$I_{B5-OUT5}$	"	"	"	
		209																$I_{B6-OUT6}$	"	"	"	
		210																$I_{B7-OUT7}$	"	"	"	

TABLE III. Group A inspection for device type 05 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation														Measured terminal	Limits	Unit
				1	2	3	4	5	6	7	8	9	10	11	12	13	14			
9 $T_A = +25^\circ C$	t_{PLH} Fig. 4	3003	211	IN ₁													OUT	IN ₁ -OUT ₁	750	ns
		212			IN ₂												OUT	IN ₂ -OUT ₂	“	“
		213				IN ₃											OUT	IN ₃ -OUT ₃	“	“
		214					IN ₄										OUT	IN ₄ -OUT ₄	“	“
		215						IN ₅									OUT	IN ₅ -OUT ₅	“	“
	t_{PHL} Fig. 4	216							IN ₆								OUT	IN ₆ -OUT ₆	“	“
		217								IN ₇							OUT	IN ₇ -OUT ₇	“	“
		3003	218	IN ₁													OUT	IN ₁ -OUT ₁	300	ns
		219			IN ₂												OUT	IN ₂ -OUT ₂	“	“
		220				IN ₃											OUT	IN ₃ -OUT ₃	“	“

NOTE: Pins not designated are open.

TABLE III. Group A inspection for device type 06.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured terminal	Min	Max	Limits
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18		
$T_A = +25^\circ\text{C}$	I_{CEX}	1																			10.0 μA	
		2																			"	
		3																			"	
		4																			"	
		5																			"	
		6																			"	
		7																			"	
		8																			"	
																					"	
																					"	
$V_{CE(\text{sat})}$	3007	9	500 μA																		1.6 V	
		10	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	OUT ₁		
		11																		OUT ₂		
		12																		OUT ₃		
		13																		OUT ₄		
		14																		OUT ₅		
		15																		OUT ₆		
		16																		OUT ₇		
																				OUT ₈		
																				"		
$V_{CE(\text{sat})}$	3007	17	350 μA																		1.3 V	
		18	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	OUT ₁		
		19																		OUT ₂		
		20																		OUT ₃		
		21																		OUT ₄		
		22																		OUT ₅		
		23																		OUT ₆		
		24																		OUT ₇		
																				OUT ₈		
																				"		
$V_{CE(\text{sat})}$	3007	25	250 μA																		1.1 V	
		26	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	OUT ₁		
		27																		OUT ₂		
		28																		OUT ₃		
		29																		OUT ₄		
		30																		OUT ₅		
		31																		OUT ₆		
		32																		OUT ₇		
																				OUT ₈		
																				"		
$I_{IN(\text{off})}$		33	25 μA																		500 μA	
		34	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA		
		35																		OUT ₁		
		36																		OUT ₂		
		37																		OUT ₃		
		38																		OUT ₄		
		39																		OUT ₅		
		40																		OUT ₆		
																				OUT ₇		
																				OUT ₈		

TABLE III. Group A inspection for device type_06 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured terminal		Limits			
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	Min	Max	Unit
1 $T_A = +25^\circ C$	I_R	41	I_{N_1}	I_{N_2}	I_{N_3}	I_{N_4}	I_{N_5}	I_{N_6}	I_{N_7}	I_{N_8}	GND	COM	OUT_8	OUT_7	OUT_6	OUT_5	OUT_4	OUT_3	OUT_2	OUT_1	0 V	0 V	μA	
		42	43	44	45	46	47	48														0 V	0 V	
		49	50	51	52	53	54	55	56													0 V	0 V	
		57	IB ₁	IB ₂	IB ₃	IB ₄	IB ₅	IB ₆	IB ₇	IB ₈											0 V	0 V		
		58	59	60	61	62	63	64														350 mA	350 mA	
		65	IC _{EX}	66	67	68	69	70	71	72												350 mA	350 mA	
		73	500 μA	74	500 μA	75	500 μA	76	77	78	79	80										500 μA	500 μA	
		3007																				500 μA	500 μA	
2 $T_A = +125^\circ C$	$V_{CE(sat)}$	73	500 μA	74	500 μA	75	500 μA	76	77	78	79	80										350 mA	350 mA	
		74																				350 mA	350 mA	
		75																				350 mA	350 mA	
		76																				350 mA	350 mA	
		77																				350 mA	350 mA	
		78																				350 mA	350 mA	
		79																				350 mA	350 mA	
		80																				350 mA	350 mA	

TABLE III. Group A inspection for device type 06 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits					
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min	Max	Unit	
$T_A = +125^\circ\text{C}$	V _{CE(sat)}	3007	81	350 μA	200 mA	200 mA	200 mA	200 mA	OUT ₁	1.5	V															
		82	83	84	85	86	87	88	89	90	91	92	93	94	95	96	97	250 μA	250 μA	250 μA	250 μA	OUT ₂	"	"		
		91	92	93	94	95	96	97	98	99	100	101	102	103	104	105	106	25 μA	25 μA	25 μA	25 μA	OUT ₃	"	"		
		107	108	109	110	111	112	113	114	115	116	117	118	119	120	105	106	107	108	109	110	OUT ₄	"	"		
		106	107	108	109	110	111	112	113	114	115	116	117	118	119	120	106	107	108	109	110	OUT ₅	"	"		
		107	108	109	110	111	112	113	114	115	116	117	118	119	120	107	108	109	110	111	112	OUT ₆	"	"		
		108	109	110	111	112	113	114	115	116	117	118	119	120	108	109	110	111	112	113	OUT ₇	"	"			
		109	110	111	112	113	114	115	116	117	118	119	120	109	110	111	112	113	114	115	116	OUT ₈	"	"		
		110	111	112	113	114	115	116	117	118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	V		
		111	112	113	114	115	116	117	118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	V			
I_R	I _R	105	106	107	108	109	110	111	112	113	114	115	116	117	118	119	120	0 V	50 V	50 V	50 V	OUT ₁	500	μA		
		106	107	108	109	110	111	112	113	114	115	116	117	118	119	120	106	0 V	50 V	50 V	50 V	OUT ₂	"	"		
		107	108	109	110	111	112	113	114	115	116	117	118	119	120	107	0 V	50 V	50 V	50 V	OUT ₃	"	"			
		108	109	110	111	112	113	114	115	116	117	118	119	120	108	0 V	50 V	50 V	50 V	OUT ₄	"	"				
		109	110	111	112	113	114	115	116	117	118	119	120	109	110	111	112	0 V	50 V	50 V	50 V	OUT ₅	"	"		
		110	111	112	113	114	115	116	117	118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	V		
		111	112	113	114	115	116	117	118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	V			
		112	113	114	115	116	117	118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	V				
		113	114	115	116	117	118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	V					
		114	115	116	117	118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	terminal	1.5	V				
V_F	V _F	113	114	115	116	117	118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	terminal	1.5	V			
		114	115	116	117	118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	terminal	1.5	V				
		115	116	117	118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	terminal	1.5	terminal	1.5	V			
		116	117	118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	terminal	1.5	terminal	1.5	terminal	1.5	V		
		117	118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	terminal	1.5	terminal	1.5	terminal	1.5	terminal	1.5	V	
		118	119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	terminal	1.5	terminal	1.5	terminal	1.5	terminal	1.5	V		
		119	120	10	11	12	13	14	15	16	17	18	terminal	1.5	terminal	1.5	terminal	1.5	terminal	1.5	terminal	1.5	terminal	1.5	V	
		120	10	11	12	13	14	15	16	17	18	terminal	1.5	terminal	1.5	V										
		10	11	12	13	14	15	16	17	18	terminal	1.5	terminal	1.5	terminal	1.5	V									
		11	12	13	14	15	16	17	18	terminal	1.5	terminal	1.5	terminal	1.5	V										
		12	13	14	15	16	17	18	terminal	1.5	terminal	1.5	terminal	1.5	terminal	1.5										

TABLE III. Group A inspection for device type_06 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation																Measured terminal	Min	Max	Unit
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16				
2 $T_A = +125^{\circ}\text{C}$	hFE	3003	121	IB_1	IB_2	IB_3	IB_4	IB_5	IB_6	IB_7	IB_8	0 V	0 V	OUT_8	OUT_7	OUT_6	OUT_5	OUT_4	OUT_3	OUT_2	OUT_1	1000	
			122									"	"									"	
			123									"	"									"	
			124									"	"									"	
			125									"	"									"	
			126									"	"									"	
			127									"	"									"	
			128									"	"									"	
			129									0 V	"									"	
			130									"	"									"	
3 $T_A = -55^{\circ}\text{C}$	I_{CEX}		131									"	"									"	
			132									"	"									"	
			133									"	"									"	
			134									"	"									"	
			135									"	"									"	
			136									"	"									"	
			137	850 μA								"	"									"	
			138	850 μA								"	"									"	
			139	850 μA								"	"									"	
			140	850 μA								"	"									"	
VCE(sat)			141	850 μA								"	"									"	
			142	850 μA								"	"									"	
			143	850 μA								"	"									"	
			144	850 μA								"	"									"	
			145	550 μA								"	"									"	
			146	550 μA								"	"									"	
			147	550 μA								"	"									"	
			148	550 μA								"	"									"	
			149	550 μA								"	"									"	
			150	550 μA								"	"									"	
VCE(sat)			151	550 μA								"	"									"	
			152	550 μA								"	"									"	
			153	350 μA								"	"									"	
			154	350 μA								"	"									"	
			155	350 μA								"	"									"	
			156	350 μA								"	"									"	
			157	350 μA								"	"									"	
			158	350 μA								"	"									"	
			159	350 μA								"	"									"	
			160																				

TABLE III. Group A inspection for device type_06 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured terminal	Min	Max	Unit		
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18			
3 $T_A = -55^\circ C$	$I_{IN(off)}$	161	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	0 V	GND	COM	OUT ₈	OUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	500 μA	
		162	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		163	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		164	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		165	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		166	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		167	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		168	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		169	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		170	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
V_F	I_R	171	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		172	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		173	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		174	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		175	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		176	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		177	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		178	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
hFE	I_B	179	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		180	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		181	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		182	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		183	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		184	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		185	I_{B1}	I_{B2}	I_{B3}	I_{B4}	I_{B5}	I_{B6}	I_{B7}	I_{B8}	0 V	350 mA	"	"	"	"	"	"	"	"	"	"	"	"
		186	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
3003	187	188	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		189	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		190	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		191	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		192	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"

TABLE III. Group A inspection for device type_06 – Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation																Measured terminal	Min	Max	Unit	
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16					
9 $T_A = +25^\circ C$	t_{PLH} Fig. 4	3003	193	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	IN ₈	GND	COM	OUT ₈	CUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	750	ns	
		3003	194	195	196	197	198	199	200	201	202	203	204	205	206	207	208						"	"
		3003	193	194	195	196	197	198	199	200	201	202	203	204	205	206	207	208					"	"
		3003	193	194	195	196	197	198	199	200	201	202	203	204	205	206	207	208					"	"
	t_{PHL} Fig. 4	3003	201	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	IN ₈									OUT	IB ₁ -OUT ₁	300	ns	
		3003	202	203	204	205	206	207	208											OUT	IB ₂ -OUT ₂	"	"	
		3003	202	203	204	205	206	207	208											OUT	IB ₃ -OUT ₃	"	"	
		3003	202	203	204	205	206	207	208											OUT	IB ₄ -OUT ₄	"	"	
																				IB ₅ -OUT ₅	"	"	"	
																				IB ₆ -OUT ₆	"	"	"	
																				IB ₇ -OUT ₇	"	"	"	
																				IB ₈ -OUT ₈	"	"	"	

NOTE: Pins not designated are open.

TABLE III. Group A inspection for device type 07.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits				
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min	Max	Unit
1	I_{CEX}	$T_A = +25^\circ C$	1	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	IN ₈	GND	COM	OUT ₈	OUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	10.0	μA		
			2																			"	"	"	
			3																			"	"	"	
			4																			"	"	"	
			5																			"	"	"	
			6																			"	"	"	
			7																			"	"	"	
			8																			"	"	"	
			V _{CE(sat)}	3007	9	500 μA																350 mA	OUT ₁	1.6	V
				10		500 μA																350 mA	OUT ₂	"	"
				11			500 μA															350 mA	OUT ₃	"	"
				12				500 μA														350 mA	OUT ₄	"	"
				13					500 μA													350 mA	OUT ₅	"	"
				14						500 μA												350 mA	OUT ₆	"	"
				15							500 μA											350 mA	OUT ₇	"	"
				16								500 μA										350 mA	OUT ₈	"	"
			V _{CE(sat)}	3007	17	350 μA																200 mA	OUT ₁	1.3	V
				18		350 μA																200 mA	OUT ₂	"	"
				19			350 μA															200 mA	OUT ₃	"	"
				20				350 μA														200 mA	OUT ₄	"	"
				21					350 μA													200 mA	OUT ₅	"	"
				22						350 μA												200 mA	OUT ₆	"	"
				23							350 μA											200 mA	OUT ₇	"	"
				24								350 μA										200 mA	OUT ₈	"	"
			V _{CE(sat)}	3007	25	250 μA																100 mA	OUT ₁	1.1	V
				26			250 μA															100 mA	OUT ₂	"	"
				27				250 μA														100 mA	OUT ₃	"	"
				28					250 μA													100 mA	OUT ₄	"	"
				29						250 μA												100 mA	OUT ₅	"	"
				30							250 μA											100 mA	OUT ₆	"	"
				31								250 μA										100 mA	OUT ₇	"	"
				32									250 μA									100 mA	OUT ₈	"	"
			$I_{IN(on)}$	33	17 V																		IN ₁	575	μA
				34		17 V																	IN ₂	"	"
				35			17 V																IN ₃	"	"
				36				17 V															IN ₄	"	"
				37					17 V														IN ₅	"	"
				38						17 V													IN ₆	"	"
				39							17 V												IN ₇	"	"
				40								17 V											IN ₈	"	"

TABLE III. Group A inspection for device type 07 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured terminal	Limits
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	
$T_A = +25^\circ C$	$I_{IN(off)}$	41	$25 \mu A$	$25 \mu A$	$25 \mu A$	$25 \mu A$	$25 \mu A$	$25 \mu A$	$25 \mu A$	$25 \mu A$	$25 \mu A$	$0 V$	$0 V$	$0 V$	$0 V$	$50 V$	$50 V$	$50 V$	$50 V$	$500 \mu A$
		42																		u
		43																		u
		44																		u
		45																		u
		46																		u
		47																		u
		48																		u
	$V_{IN(on)}$	49	$13 V$	$13 V$	$13 V$	$13 V$	$13 V$	$13 V$	$13 V$	$13 V$	$13 V$	$0 V$	$50 V$	$0 V$	$0 V$	$300 mA$	$300 mA$	$300 mA$	$300 mA$	$2.0 V$
		50																		u
I_R		51																		u
		52																		u
		53																		u
		54																		u
		55																		u
		56																		u
		57																		u
		58																		u
		59																		u
		60																		u
V_F		61																		u
		62																		u
		63																		u
		64																		u
		65																		u
		66																		u
		67																		u
		68																		u
		69																		u
		70																		u
hFE		71																		u
		72																		u
		73	IB_1	IB_2	IB_3	IB_4	IB_5	IB_6	IB_7	IB_8		$0 V$	$350 mA$	$1000 \mu A$						
		74																		u
		75																		u
		76																		u
		77																		u
		78																		u
		79																		u
		80																		u

TABLE III. Group A inspection for device type 07 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits			
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min	Max
$T_A = +125^\circ\text{C}$	I_{CEX}	81	IN_1	IN_2	IN_3	IN_4	IN_5	IN_6	IN_7	IN_8	GND	COM	OUT_8	OUT_7	OUT_6	OUT_5	OUT_4	OUT_3	OUT_2	OUT_1	50 V	50 V	10.0 μA	
		82									"											"	"	"
		83									"											"	"	"
		84									"											"	"	"
		85									"											"	"	"
		86									"											"	"	"
		87									"											"	"	"
		88									"											"	"	"
		89	500 μA								"											350 mA	350 mA	1.8 V
		90	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 mA	350 mA	350 mA	
V _{CE(sat)}	3007	91																						
		92																						
		93																						
		94																						
		95																						
		96																						
		97	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 mA	350 mA	350 mA	
		98																						
		99																						
V _{CE(sat)}	3007	100																						
		101																						
		102																						
		103																						
		104																						
		105	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	200 mA	200 mA	200 mA	
		106																						
		107																						
		108																						
		109																						
$I_{IN(on)}$	110																							
	111																							
	112																							
	113	17 V																						
	114		17 V																					
	115			17 V																				
	116				17 V																			
	117					17 V																		
	118						17 V																	
	119							17 V																
	120								17 V															

TABLE III. Group A inspection for device type 07 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits			
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min	Max
$T_A = +125^\circ C$	$I_{IN(off)}$	121	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	0 V	0 V	0 V	0 V	0 V	0 V	50 V	50 V	50 V	OUT ₁	500	μA	
		122																				OUT ₂		
		123																			OUT ₃			
		124																			OUT ₄			
		125																			OUT ₅			
		126																			OUT ₆			
		127																			OUT ₇			
		128																			OUT ₈			
	$V_{IN(on)}$	129	13 V	13 V	13 V	13 V	13 V	13 V	13 V	13 V	13 V	13 V	0 V	0 V	0 V	0 V	0 V	0 V	300 mA	300 mA	300 mA	OUT ₁	2.0	V
		130																			OUT ₂			
I_R		131																			OUT ₃			
		132																			OUT ₄			
		133																			OUT ₅			
		134																			OUT ₆			
		135																			OUT ₇			
		136																			OUT ₈			
		137																					10.0	μA
		138																						
		139																						
		140																						
V_F		141																						
		142																						
		143																						
		144																						
		145																						
		146																						
		147																						
		148																						
		149																						
		150																						
hFE		151																						
		152																						
		153	IB_1	IB_2	IB_3	IB_4	IB_5	IB_6	IB_7	IB_8														
		154																						
		155																						
		156																						
		157																						
		158																						
		159																						
		160																						

TABLE III. Group A inspection for device type 07 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits			
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min	Max
3 $T_A = -55^\circ C$	I_{CEX}	161	IN_1																				10.0	μA
		162	IN_2	IN_3	IN_4	IN_5	IN_6	IN_7	IN_8	GND	COM	OUT_8	OUT_7	OUT_6	OUT_5	OUT_4	OUT_3	OUT_2	OUT_1			"	"	
		163								"	"											"	"	
		164								"	"											"	"	
		165								"	"											"	"	
		166								"	"											"	"	
		167								"	"											"	"	
		168								"	"											"	"	
		3007	169	850 μA						"	"													
		170		850 μA																				
VCE(sat)		171																						
		172																						
		173																						
		174																						
		175																						
		176																						
		3007	177	550 μA						"	"													
		178		550 μA																				
		179																						
		180																						
VCE(sat)		181																						
		182																						
		183																						
		184																						
		3007	185	350 μA						"	"													
		186		350 μA																				
		187																						
		188																						
		189																						
		190																						
$I_{IN(on)}$		191																						
		192																						
		193	17 V							"	"													
		194		17 V						"	"													
		195								"	"													
		196								"	"													
		197								"	"													
		198								"	"													
		199								"	"													
200																								

TABLE III. Group A inspection for device type 07 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured limits		Unit
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18
3 $T_A = -55^\circ C$	$I_{IN(off)}$	201	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	50 V	50 V	500 μA	
		202	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	"
		203	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	OUT ₄	"
		204	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	"
		205	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	OUT ₈	"
		206	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		207	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		208	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		209	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	18 V	300 mA	300 mA	2.0 V
		210	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	"
4	$V_{IN(on)}$	211	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	OUT ₄	"
		212	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	"
		213	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	OUT ₈	"
		214	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		215	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		216	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		217	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	10.0 μA	"
		218	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		219	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		220	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
5	I_R	221	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		222	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		223	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		224	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		225	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	2.0 V	
		226	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	"	
		227	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	OUT ₄	"	
		228	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	"	
		229	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	OUT ₈	"	
		230	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
6	V_F	231	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA	2.0 V	
		232	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	"	
		233	IB ₁	IB ₂	IB ₃	IB ₄	IB ₅	IB ₆	IB ₇	IB ₈	"	"	"	"	"	"	"	IB ₁ -OUT ₁	IB ₂ -OUT ₂	"	
		234	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IB ₃ -OUT ₃	IB ₄ -OUT ₄	"	
		235	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IB ₅ -OUT ₅	IB ₆ -OUT ₆	"	
		236	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IB ₇ -OUT ₇	IB ₈ -OUT ₈	"	
		237	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		238	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		239	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		240	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"

TABLE III. Group A inspection for device type 07 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation																Measured terminal	Min	Max	Unit	
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16					
9 $T_A = +25^\circ C$	t_{PLH} Fig. 4	3003	241	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	IN ₈	GND	COM	OUT ₈	CUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	750	ns	
		242										0 V								OUT	OUT	OUT	"	"
		243										"								OUT	OUT	OUT	"	"
		244										"								OUT	OUT	OUT	"	"
		245										"								OUT	OUT	OUT	"	"
		246										"								OUT	OUT	OUT	"	"
		247										"								OUT	OUT	OUT	"	"
		248										"								OUT	OUT	OUT	"	"
	t_{PHL} Fig. 4	3003	249	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	IN ₈									OUT	OUT	OUT	ns	ns
		250										"								OUT	OUT	OUT	"	"
		251										"								OUT	OUT	OUT	"	"
		252										"								OUT	OUT	OUT	"	"
		253										"								OUT	OUT	OUT	"	"
		254										"								OUT	OUT	OUT	"	"
		255										"								OUT	OUT	OUT	"	"
		256										"								OUT	OUT	OUT	"	"

NOTE: Pins not designated are open.

TABLE III. Group A inspection for device type 08.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured terminal	Min	Max	Limits
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18		
$T_A = +25^\circ\text{C}$	I_{CEX}	1																			10.0 μA	
		2																			"	
		3																			"	
		4																			"	
		5																			"	
		6																			"	
		7																			"	
		8																			"	
																					"	
																					"	
$V_{CE(\text{sat})}$	3007	9	500 μA																		1.6 V	
		10	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	OUT ₁		
		11																			"	
		12																			"	
		13																			"	
		14																			"	
		15																			"	
		16																			"	
																					"	
																					"	
$V_{CE(\text{sat})}$	3007	17	350 μA																		1.3 V	
		18	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	OUT ₁		
		19																			"	
		20																			"	
		21																			"	
		22																			"	
		23																			"	
		24																			"	
																					"	
																					"	
$V_{CE(\text{sat})}$	3007	25	250 μA																		1.1 V	
		26	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	OUT ₁		
		27																			"	
		28																			"	
		29																			"	
		30																			"	
		31																			"	
		32																			"	
																					"	
																					"	
$I_{IN(\text{on})}$	33	3.85 V	3.85 V																		650 μA	
	34		3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	1350 μA		
	35																				"	
	36																				"	
	37																				"	
	38																				"	
	39																				"	
	40																				"	

TABLE III. Group A inspection for device type 08 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits						
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min	Max	Unit		
1 $T_A = +25^\circ C$	$I_{IN(off)}$	41	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	0 V	0 V	50 V	50 V	50 V	OUT ₁	500	μA				
		42															"	"	"	"	"	OUT ₂	"	"			
		43															"	"	"	"	"	OUT ₃	"	"			
		44															"	"	"	"	"	OUT ₄	"	"			
		45															"	"	"	"	"	OUT ₅	"	"			
		46															"	"	"	"	"	OUT ₆	"	"			
		47															"	"	"	"	"	OUT ₇	"	"			
		48															"	"	"	"	"	OUT ₈	"	"			
	$V_{IN(on)}$	49	2.0 V														0 V										
		50		2.0 V													"										
		51			2.0 V												"										
		52				2.0 V											"										
		53					2.0 V										"										
		54						2.0 V									"										
		55							2.0 V								"										
		56								2.0 V							"										
	$V_{IN(on)}$	57	2.2 V														0 V										
		58		2.2 V													"										
		59			2.2 V												"										
		60				2.2 V											"										
		61					2.2 V										"										
		62						2.2 V									"										
		63							2.2 V								"										
		64								2.2 V							"										
	$V_{IN(on)}$	65	2.4 V														0 V										
		66		2.4 V													"										
		67			2.4 V												"										
		68				2.4 V											"										
		69					2.4 V										"										
		70						2.4 V									"										
		71							2.4 V								"										
		72								2.4 V							"										
	I_R	73															0 V	50 V									
		74															"	"									
		75															"	"									
		76															"	"									
		77															"	"									
		78															"	"									
		79															"	"									
		80															"	"									

TABLE III. Group A inspection for device type 08 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits					
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min	Max	Unit	
1 $T_A = +25^\circ C$	V_F	81	I_{N_1}	I_{N_2}	I_{N_3}	I_{N_4}	I_{N_5}	I_{N_6}	I_{N_7}	I_{N_8}	GND	COM	OUT_8	CUT_7	OUT_6	OUT_5	OUT_4	OUT_3	OUT_2	OUT_1	350 mA	350 mA	350 mA	2.0 V		
		82									"	"	0 V	0 V									"	"	"	
		83									"	"											"	"	"	
		84									"	"											"	"	"	
		85									"	"											"	"	"	
		86									"	"											"	"	"	
		87									"	"											"	"	"	
		88									"	"											"	"	"	
hFE	3003	89	IB_1	IB_2	IB_3	IB_4	IB_5	IB_6	IB_7	IB_8												350 mA	350 mA	350 mA	1000	
		90									"	"											"	"	"	
		91									"	"											"	"	"	
		92									"	"											"	"	"	
		93									"	"											"	"	"	
		94									"	"											"	"	"	
		95									"	"											"	"	"	
		96									"	"											"	"	"	
$T_A = +125^\circ C$	ICEx	97											0 V										50 V	50 V	50 V	10.0 μA
		98									"	"											"	"	"	
		99									"	"											"	"	"	
		100									"	"											"	"	"	
		101									"	"											"	"	"	
		102									"	"											"	"	"	
		103									"	"											"	"	"	
		104									"	"											"	"	"	
VCE(sat)	3007	105	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	350 mA	350 mA	350 mA	350 mA			
		106									"	"											"	"	"	
		107									"	"											"	"	"	
		108									"	"											"	"	"	
		109									"	"											"	"	"	
		110									"	"											"	"	"	
		111									"	"											"	"	"	
		112									"	"											"	"	"	
VCE(sat)	3007	113	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	200 mA	200 mA	200 mA	200 mA			
		114									"	"											"	"	"	
		115									"	"											"	"	"	
		116									"	"											"	"	"	
		117									"	"											"	"	"	
		118									"	"											"	"	"	
		119									"	"											"	"	"	
		120									"	"											"	"	"	

TABLE III. Group A inspection for device type 08 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation														Measured terminal		Limits					
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	Min	Max	Unit
2 $T_A = +125^\circ C$	$V_{CE(\text{sat})}$	3007	121	250 μA	0 V	IN ₈	IN ₆	IN ₅	IN ₄	IN ₃	IN ₂	IN ₁	OUT ₁	OUT ₂	V									
		122	123	124	125	126	127	128					GND	COM	OUT ₈	OUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	1.3	
		129	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	0 V	u	u	u	u	u	u	u	u	u		
		130	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA		
		131																						
		132																						
		133																						
		134																						
	$I_{IN(\text{on})}$	135																						
		136																						
		137	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V		
		138																						
		139																						
		140																						
		141																						
		142																						
		143																						
	$I_{IN(\text{off})}$	144																						
		145	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	0 V	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	
		146																						
		147																						
		148																						
		149																						
		150																						
		151																						
		152																						
$V_{IN(\text{on})}$		153	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	2.2 V	0 V	250 mA	250 mA	250 mA	250 mA	250 mA	250 mA	250 mA	250 mA	250 mA	2.0 V	
		154																						
		155																						
		156																						
		157																						
		158																						
		159																						
		160																						

TABLE III. Group A inspection for device type 08 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured terminal	Min	Max	Limits	
			IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	IN ₈	GND	COM	OUT ₈	OUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁			
2 $T_A = +125^\circ C$	$V_{IN(on)}$	161	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	0 V	2.0 V	u	u
		162																				u	u
		163																				u	u
		164																				u	u
		165																				u	u
		166																				u	u
		167																				u	u
		168																				u	u
	I_R	169																				10.0 μA	
		170																				u	u
V_F		171																				u	u
		172																				u	u
		173																				u	u
		174																				u	u
		175																				u	u
		176																				u	u
		177																				u	u
		178																				u	u
		179																				u	u
		180																				u	u
hFE		181																				u	u
		182																				u	u
		183																				u	u
		184																				u	u
		3003	185	IB ₁	IB ₂	IB ₃	IB ₄	IB ₅	IB ₆	IB ₇	IB ₈										1000		
		186	187																				
		188	189																				
		190	191																				
		192																					

TABLE III. Group A inspection for device type 08 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits			
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min	Max
3 $T_A = -55^{\circ}\text{C}$	I_{CEX}	193	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	IN ₈	GND	COM	OUT ₈	OUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	50 V	10.0 μA		
		194									0 V												"	"
		195									"												"	"
		196									"												"	"
		197									"												"	"
		198									"												"	"
		199									"												"	"
		200									"												"	"
		201	850 μA								"													
		202	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	850 μA	350 mA	350 mA	1.8 V
V _{CE(sat)}		203																						
		204																						
		205																						
		206																						
		207																						
		208																						
		209	550 μA																					
		210	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	550 μA	200 mA	200 mA	1.5 V
V _{CE(sat)}		211																						
		212																						
		213																						
		214																						
		215																						
		216																						
		217	350 μA																					
		218	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	200 mA	200 mA	1.5 V
I _{IN(on)}		219																						
		220																						
		221																						
		222																						
		223																						
		224																						
		225	3.85 V																					
		226	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	3.85 V	1350 μA

TABLE III. Group A inspection for device type 08 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits			
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min	Max
3 $T_A = -55^{\circ}\text{C}$	$I_{IN(\text{off})}$	233	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	0 V	0 V	0 V	0 V	0 V	50 V	50 V	50 V	50 V	OUT ₁	500 μA		
		234																				OUT ₂	"	
		235																				OUT ₃	"	
		236																				OUT ₄	"	
		237																				OUT ₅	"	
		238																				OUT ₆	"	
		239																				OUT ₇	"	
		240																				OUT ₈	"	
	$V_{IN(\text{on})}$	241	2.6 V									0 V										200 mA	OUT ₁	2.0 V
		242	2.6 V	2.6 V	2.6 V	2.6 V	2.6 V	2.6 V	2.6 V	2.6 V	2.6 V	0 V										OUT ₂	"	
4 $T_A = 25^{\circ}\text{C}$		243																				OUT ₃	"	
		244																				OUT ₄	"	
		245																				OUT ₅	"	
		246																				OUT ₆	"	
		247																				OUT ₇	"	
		248																				OUT ₈	"	
	$V_{IN(\text{on})}$	249	2.8 V									0 V										250 mA	OUT ₁	2.0 V
		250	2.8 V	2.8 V	2.8 V	2.8 V	2.8 V	2.8 V	2.8 V	2.8 V	2.8 V	0 V										OUT ₂	"	
		251																				OUT ₃	"	
		252																				OUT ₄	"	
		253																				OUT ₅	"	
5 $T_A = 125^{\circ}\text{C}$		254																				OUT ₆	"	
		255																				OUT ₇	"	
		256																				OUT ₈	"	
	$V_{IN(\text{on})}$	257	3.0 V									0 V										300 mA	OUT ₁	2.0 V
		258	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	0 V										OUT ₂	"	
		259																				OUT ₃	"	
		260																				OUT ₄	"	
		261																				OUT ₅	"	
		262																				OUT ₆	"	
		263																				OUT ₇	"	
		264																				OUT ₈	"	
6 $T_A = 150^{\circ}\text{C}$	I_R	265																			0 V	COM	10.0 μA	
		266																			COM	"		
		267																			COM	"		
		268																			COM	"		
		269																			COM	"		
		270																			COM	"		
		271																			COM	"		
		272																			COM	"		

TABLE III. Group A inspection for device type 08 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured limits		Unit	
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18		
3 $T_A = -55^\circ C$	V_F	273	IN_1	IN_2	IN_3	IN_4	IN_5	IN_6	IN_7	IN_8	GND	COM	OUT ₈	OUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	350 mA	2.0 V
		274									0 V	0 V									OUT ₁ OUT ₂ OUT ₃ OUT ₄ OUT ₅ OUT ₆ OUT ₇ OUT ₈	
		275																				
		276																				
		277																				
		278																				
		279																				
		280																				
4 t_{PLH}	t_{PLH}	281	IB_1	IB_2	IB_3	IB_4	IB_5	IB_6	IB_7	IB_8											350 mA	500 ns
		282																				
		283																				
		284																				
		285																				
		286																				
		287																				
		288																				
5 $T_A = +25^\circ C$	t_{PHL}	289	IN_1	IN_2	IN_3	IN_4	IN_5	IN_6	IN_7	IN_8											OUT	ns
		290																				
		291																				
		292																				
		293																				
		294																				
		295																				
		296																				
6 t_{PHL}	t_{PHL}	297	IN_1	IN_2	IN_3	IN_4	IN_5	IN_6	IN_7	IN_8											OUT	ns
		298																				
		299																				
		300																				
		301																				
		302																				
7 t_{PHL}	t_{PHL}	303	IN_1	IN_2	IN_3	IN_4	IN_5	IN_6	IN_7	IN_8											300 ns	
		304																				

NOTE: Pins not designated are open.

TABLE III. Group A inspection for device type 09.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured terminal	Min	Max	Unit	
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18			
$T_A = +25^\circ\text{C}$	I_{CEX}	1									0 V							50 V			10.0 μA		
		2									"										"		
		3									"										"		
		4									"										"		
		5									"										"		
		6									"										"		
		7									"										"		
		8									"										"		
	$V_{CE(\text{sat})}$	3007	9	500 μA							"								350 mA	OUT ₁	1.6 V		
		10	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	OUT ₁	"	"	
$V_{CE(\text{sat})}$		11									"										"	"	"
		12									"										"	"	"
		13									"										"	"	"
		14									"										"	"	"
		15									"										"	"	"
		16									"										"	"	"
		17	350 μA								"										"	"	"
		18	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	OUT ₁	1.3 V	
$V_{CE(\text{sat})}$		19									"										"	"	"
		20									"										"	"	"
		21									"										"	"	"
		22									"										"	"	"
		23									"										"	"	"
		24									"										"	"	"
		25	250 μA								"										"	"	"
		26	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	OUT ₁	1.1 V	
$I_{IN(on)}$		27									"										"	"	"
		28									"										"	"	"
		29									"										"	"	"
		30									"										"	"	"
		31									"										"	"	"
		32									"										"	"	"
		33	5.0 V								"										"	"	"
		34	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	500 μA		

TABLE III. Group A inspection for device type 09 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured terminal		Limits			
			Test no.	IN ₁	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	Min	Max	Unit
1 $T_A = +25^\circ C$	IN(on)	41	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	750	1450	μA
		42																				"	"	"
		43																				"	"	"
		44																				"	"	"
		45																				"	"	"
		46																				"	"	"
		47																				"	"	"
		48																				"	"	"
	IN(off)	49	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	50 V	50 V	500 μA		
		50																				"	"	"
2 $T_A = +25^\circ C$	V _{IN(on)}	51																				"	"	"
		52																				"	"	"
		53																				"	"	"
		54																				"	"	"
		55																				"	"	"
		56																				"	"	"
		57	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	125 mA	125 mA	2.0 V	
		58																				"	"	"
		59																				"	"	"
		60																				"	"	"
3 $T_A = +25^\circ C$	V _{IN(off)}	61																				"	"	"
		62																				"	"	"
		63																				"	"	"
		64																				"	"	"
		65	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	200 mA	200 mA	2.0 V	
		66																				"	"	"
		67																				"	"	"
		68																				"	"	"
		69																				"	"	"
		70																				"	"	"
4 $T_A = +25^\circ C$	V _{IN(on)}	71																				"	"	"
		72																				"	"	"
		73	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	275 mA	275 mA	2.0 V	
		74																				"	"	"
		75																				"	"	"
		76																				"	"	"
		77																				"	"	"
		78																				"	"	"
		79																				"	"	"
		80																				"	"	"

TABLE III. Group A inspection for device type 09 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured limits		Unit
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18
1 $T_A = +25^\circ C$	$V_{IN(on)}$	81	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	350 mA	350 mA	2.0 V
		82	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	"
		83	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	OUT ₄	"
		84	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	"
		85	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	OUT ₈	"
		86	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		87	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		88	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		89	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	10.0 μA
		90	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
2 $T_A = +125^\circ C$	I_{RE}	91	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		92	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		93	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		94	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		95	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		96	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		97	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	2.0 V
		98	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	OUT ₄	"
		99	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	"
		100	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	OUT ₈	"
2 $T_A = +125^\circ C$	V_F	101	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		102	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		103	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		104	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		105	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		106	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		107	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		108	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		109	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		110	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
2 $T_A = +125^\circ C$	hFE	111	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		112	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		113	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		114	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		115	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		116	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		117	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		118	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		119	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"
		120	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	COM	"

TABLE III. Group A inspection for device type 09 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation														Limits		Measured terminal	Min	Max	Unit					
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18						
$T_A = +125^\circ\text{C}$	VCE(sat)	3007	121	500 μA	350 mA	350 mA	350 mA	350 mA	350 mA	350 mA	OUT ₁	1.8	V														
			122	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₂	"	"		
			123	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	"	"		
			124	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₄	"	"		
			125	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	"	"		
			126	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₆	"	"		
			127	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	"	"		
			128	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₈	"	"		
			3007	129	350 μA	350 mA	350 mA	350 mA	350 mA	350 mA	350 mA	OUT ₁	1.8	V													
	VCE(sat)		130	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₂	"	"		
			131	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	"	"		
			132	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₄	"	"		
			133	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	"	"		
			134	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₆	"	"		
			135	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	"	"		
			136	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₈	"	"		
			3007	137	250 μA	200 mA	200 mA	200 mA	200 mA	200 mA	200 mA	OUT ₁	1.5	V													
			138	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₂	"	"		
			139	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	"	"		
			140	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₄	"	"		
			141	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	"	"		
			142	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₆	"	"		
			143	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	"	"		
			144	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₈	"	"		
IN(on)	145	5.0 V	146	5.0 V	100 mA	100 mA	100 mA	100 mA	100 mA	100 mA	OUT ₁	1.3	V														
			147	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₂	"	"		
			148	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	"	"		
			149	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₄	"	"		
			150	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	"	"		
			151	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₆	"	"		
			152	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	"	"		
			153	12 V	12 V	12 V	12 V	12 V	12 V	IN ₁	750	μA															
			154	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₂	"	"		
IN(on)	155	12 V	156	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₃	"	"		
			157	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₄	"	"		
			158	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₅	"	"		
			159	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₆	"	"		
			160	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₇	"	"		
			"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₈	"	"		

TABLE III. Group A inspection for device type 09 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits		
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min
2 $T_A = +125^\circ C$	$I_{IN(off)}$	161	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	0 V	0 V	50 V	50 V	50 V	OUT ₁	500 μA	
		162	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₂	"
		163	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	"
		164	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₄	"
		165	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	"
		166	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₆	"
		167	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	"
		168	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₈	"
		169	5.0 V	"	"	"	"	"	"	"	"	"	"	"	"	"	0 V	"	"	"	"	125 mA	125 mA
		170	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	0 V	"	"	"	"	125 mA	125 mA
$V_{IN(on)}$	$V_{IN(on)}$	171	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	125 mA	125 mA
		172	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	125 mA	125 mA
		173	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	125 mA	125 mA
		174	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	125 mA	125 mA
		175	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	125 mA	125 mA
		176	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	125 mA	125 mA
		177	6.0 V	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA
		178	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	0 V	"	"	"	"	200 mA	200 mA
		179	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA
		180	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA
$V_{IN(on)}$	$V_{IN(on)}$	181	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA
		182	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA
		183	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA
		184	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	200 mA	200 mA
		185	7.0 V	"	"	"	"	"	"	"	"	"	"	"	"	"	0 V	"	"	"	"	275 mA	275 mA
		186	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	0 V	"	"	"	"	275 mA	275 mA
		187	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	275 mA	275 mA
		188	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	275 mA	275 mA
		189	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	275 mA	275 mA
		190	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	275 mA	275 mA
$V_{IN(on)}$	$V_{IN(on)}$	191	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	275 mA	275 mA
		192	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	275 mA	275 mA
		193	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	0 V	"	"	"	"	350 mA	350 mA
		194	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA
		195	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA
		196	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA
		197	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA
		198	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA
		199	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA
		200	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	350 mA	350 mA

TABLE III. Group A inspection for device type 09 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Test no.	Pin number and signal designation																Measured terminal	Min	Max	Limits
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16				
2 $T_A = +125^\circ C$	I_R	201										0 V	50 V				0 V	0 V	0 V	COM	10.0 μA		
		202										"	"							COM	"	"	"
		203										"	"							COM	"	"	"
		204										"	"							COM	"	"	"
		205										"	"							COM	"	"	"
	V_F	206										"	"							COM	"	"	"
		207										"	"							COM	"	"	"
		208										"	"							COM	"	"	"
		209										"	"							COM	10.0 μA		
		210										"	"							COM	"	"	"
3 $T_A = -55^\circ C$	hFE	211										"	"							COM	"	"	"
		212										"	"							COM	"	"	"
		213										"	"							COM	"	"	"
		214										"	"							COM	"	"	"
		215										"	"							COM	"	"	"
	I_{CEX}	216										"	"							COM	"	"	"
		217	IB_1	IB_2	IB_3	IB_4	IB_5	IB_6	IB_7	IB_8										COM	"	"	"
		218										"	"							COM	"	"	"
		219										"	"							COM	"	"	"
		220										"	"							COM	"	"	"
4	$V_{CE(sat)}$	221										"	"							COM	"	"	"
		222										"	"							COM	"	"	"
		223										"	"							COM	"	"	"
		224										"	"							COM	"	"	"
		225										"	"							COM	"	"	"
	V_{BE}	226										"	"							COM	"	"	"
		227										"	"							COM	"	"	"
		228										"	"							COM	"	"	"
		229										"	"							COM	"	"	"
		230										"	"							COM	"	"	"
5	I_{CBO}	231										"	"							COM	"	"	"
		232										"	"							COM	"	"	"
		233	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	$850 \mu A$	"	"	"
		234																		COM	"	"	"
		235																		COM	"	"	"
	I_{CBO}	236																		COM	"	"	"
		237																		COM	"	"	"
		238																		COM	"	"	"
		239																		COM	"	"	"
		240																		COM	"	"	"

TABLE III. Group A inspection for device type 09 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits		
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min
3 $T_A = -55^{\circ}\text{C}$	VCE(sat)	3007	241	550 μA	200 mA	200 mA	200 mA	OUT ₁	15	V													
		3007	242	550 μA	200 mA	200 mA	200 mA	OUT ₂	u	u													
		243																	OUT ₃	u	u	u	
		244																	OUT ₄	u	u	u	
		245																	OUT ₅	u	u	u	
	VCE(sat)	246																	OUT ₆	u	u	u	
		247																	OUT ₇	u	u	u	
		248																	OUT ₈	u	u	u	
		3007	249	350 μA	100 mA	100 mA	100 mA	OUT ₁	1.3	V													
		3007	250																OUT ₂	u	u	u	
IN(on)	I _{IN} (on)	251																	OUT ₃	u	u	u	
		252																	OUT ₄	u	u	u	
		253																	OUT ₅	u	u	u	
		254																	OUT ₆	u	u	u	
		255																	OUT ₇	u	u	u	
		256																	OUT ₈	u	u	u	
	I _{IN} (off)	257	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	5.0 V	IN ₁	250	500	μA	
		258																	IN ₂	u	u	u	
		259																	IN ₃	u	u	u	
		260																	IN ₄	u	u	u	
		261																	IN ₅	u	u	u	
IN(off)	I _{IN} (off)	262																	IN ₆	u	u	u	
		263																	IN ₇	u	u	u	
		264																	IN ₈	u	u	u	
		265	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	12 V	IN ₁	750	1450	μA	
	I _{IN} (off)	266																	IN ₂	u	u	u	
		267																	IN ₃	u	u	u	
		268																	IN ₄	u	u	u	
		269																	IN ₅	u	u	u	
IN(off)	I _{IN} (off)	270																	IN ₆	u	u	u	
		271																	IN ₇	u	u	u	
		272																	IN ₈	u	u	u	
		273	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	50 V	50 V	50 V	50 V	500 μA	
	I _{IN} (off)	274																	OUT ₁	u	u	u	
		275																	OUT ₂	u	u	u	
		276																	OUT ₃	u	u	u	
		277																	OUT ₄	u	u	u	
IN(off)	I _{IN} (off)	278																	OUT ₅	u	u	u	
		279																	OUT ₆	u	u	u	
		280																	OUT ₇	u	u	u	
																			OUT ₈	u	u	u	

TABLE III. Group A inspection for device type 09 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits			
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min	Max
3 $T_A = -55^{\circ}\text{C}$	$V_{IN(on)}$	281	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	6.0 V	125 mA	125 mA	125 mA	OUT ₁	2.0	V	
		282	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₂	OUT ₃	OUT ₄	OUT ₅	"	"
		283	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₆	OUT ₇	OUT ₈	OUT ₁	"	"
		284	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		285	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		286	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		287	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		288	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		289	8.0 V	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		290	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	8.0 V	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
3 $T_A = 25^{\circ}\text{C}$	$V_{IN(on)}$	291	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		292	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		293	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		294	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		295	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		296	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		297	10.0 V	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		298	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	10.0 V	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		299	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		300	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
3 $T_A = 55^{\circ}\text{C}$	$V_{IN(on)}$	301	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		302	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		303	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		304	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		305	12.0 V	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		306	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	12.0 V	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		307	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		308	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		309	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		310	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
3 $T_A = 100^{\circ}\text{C}$	I_R	311	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		312	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		313	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		314	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		315	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		316	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		317	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		318	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"
		319	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	OUT ₂	OUT ₃	OUT ₄	"	"
		320	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	OUT ₆	OUT ₇	OUT ₈	"	"

TABLE III. Group A inspection for device type 09 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured limits		Unit		
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18			
3	$T_A = -55^\circ C$	321	IN_1	IN_2	IN_3	IN_4	IN_5	IN_6	IN_7	IN_8	GND	COM	OUT ₈	CUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	350 mA	2.0 V	
		322									"	"	0 V								OUT ₁	OUT ₂	"
		323									"	"									OUT ₃	OUT ₄	"
		324									"	"									OUT ₅	OUT ₆	"
		325									"	"									OUT ₇	OUT ₈	"
		326									"	"											"
		327									"	"											"
		328									"	"											"
86	t_{PLH}	329	IB_1	IB_2	IB_3	IB_4	IB_5	IB_6	IB_7	IB_8											350 mA	500 ns	
		330									"	"										350 mA	"
		331									"	"										350 mA	"
		332									"	"										350 mA	"
		333									"	"										350 mA	"
		334									"	"										350 mA	"
		335									"	"										350 mA	"
		336									"	"										350 mA	"
9	$T_A = +25^\circ C$	337	IN_1	IN_2	IN_3	IN_4	IN_5	IN_6	IN_7	IN_8											OUT	ns	
		338									"	"									OUT	"	
		339									"	"									OUT	"	
		340									"	"									OUT	"	
		341									"	"									OUT	"	
		342									"	"									OUT	"	
		343									"	"									OUT	"	
		344									"	"									OUT	"	
86	t_{PHL}	345	IN_1	IN_2	IN_3	IN_4	IN_5	IN_6	IN_7	IN_8											OUT	ns	
		346									"	"									OUT	"	
		347									"	"									OUT	"	
		348									"	"									OUT	"	
		349									"	"									OUT	"	
		350									"	"									OUT	"	
		351									"	"									OUT	"	
		352									"	"									OUT	"	

NOTE: Pins not designated are open.

TABLE III. Group A inspection for device type 10.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured terminal	Min	Max	Limits
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18		
$T_A = +25^\circ\text{C}$	I_{CEX}	1									0 V							50 V			10.0 μA	
		2									"								OUT ₁	"	"	"
		3									"								OUT ₂	"	"	"
		4									"								OUT ₃	"	"	"
		5									"								OUT ₄	"	"	"
		6									"								OUT ₅	"	"	"
		7									"								OUT ₆	"	"	"
		8									"								OUT ₇	"	"	"
	$V_{CE(\text{sat})}$	9	500 μA								"								350 mA	OUT ₁	1.6	V
		10	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	500 μA	"								OUT ₂	"	"	"
		11									"								OUT ₃	"	"	"
		12									"								OUT ₄	"	"	"
		13									"								OUT ₅	"	"	"
		14									"								OUT ₆	"	"	"
		15									"								OUT ₇	"	"	"
		16									"								OUT ₈	"	"	"
$V_{CE(\text{sat})}$	$V_{CE(\text{sat})}$	17	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	"								200 mA	OUT ₁	1.3	V
		18									"								OUT ₂	"	"	"
		19									"								OUT ₃	"	"	"
		20									"								OUT ₄	"	"	"
		21									"								OUT ₅	"	"	"
		22									"								OUT ₆	"	"	"
		23									"								OUT ₇	"	"	"
		24									"								OUT ₈	"	"	"
	$I_{IN(on)}$	25	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	"								100 mA	OUT ₁	1.1	V
		26									"								OUT ₂	"	"	"
		27									"								OUT ₃	"	"	"
		28									"								OUT ₄	"	"	"
		29									"								OUT ₅	"	"	"
		30									"								OUT ₆	"	"	"
		31									"								OUT ₇	"	"	"
		32									"								OUT ₈	"	"	"
$I_{IN(on)}$	$I_{IN(on)}$	33	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	"								IN ₁	1180	2400	μA
		34									"								IN ₂	"	"	"
		35									"								IN ₃	"	"	"
		36									"								IN ₄	"	"	"
		37									"								IN ₅	"	"	"
		38									"								IN ₆	"	"	"
		39									"								IN ₇	"	"	"
		40									"								IN ₈	"	"	"

TABLE III. Group A inspection for device type 10 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured limits		Min	Max	Unit	
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18			
1 $T_A = +25^\circ C$	$I_{IN(off)}$	41	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	0 V	GND	COM	OUT ₈	CUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	500 μA	
		42										"											"	"
		43										"											"	"
		44										"											"	"
		45										"											"	"
		46										"											"	"
		47										"											"	"
		48										"											"	"
		49	2.4 V									"											350 mA	350 mA
		50	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.4 V	2.0 V	
$V_{IN(on)}$		51										"											"	"
		52										"											"	"
		53										"											"	"
		54										"											"	"
		55										"											"	"
		56										"											"	"
		57										"											"	"
		58										"											"	"
		59										"											"	"
		60										"											"	"
I_R		61										"											"	"
		62										"											"	"
		63										"											"	"
		64										"											"	"
		65										"											"	"
		66										"											"	"
		67										"											"	"
		68										"											"	"
		69										"											"	"
		70										"											"	"
V_F		71										"											"	"
		72										"											"	"
		73	IB_1	IB_2	IB_3	IB_4	IB_5	IB_6	IB_7	IB_8														
		74																						
		75																						
		76																						
		77																						
		78																						
		79																						
		80																						
hFE		3003																						
		73																						
		74																						
		75																						
		76																						
		77																						
		78																						
		79																						
		80																						

TABLE III. Group A inspection for device type 10 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits			
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min	Max
$T_A = +125^\circ\text{C}$	I_{CEX}	81	IN_1																50 V	50 V	OUT ₁	10.0	μA	
		82	IN_2																	OUT ₂	"		"	
		83																	OUT ₃	"		"		
		84																	OUT ₄	"		"		
		85																	OUT ₅	"		"		
		86																	OUT ₆	"		"		
		87																	OUT ₇	"		"		
		88																	OUT ₈	"		"		
		3007	89	500 μA															350 mA	350 mA	OUT ₁	1.8	V	
		90		500 μA	500 mA	350 mA	OUT ₂	"																
$V_{CE}(\text{sat})$		91																	OUT ₃	"		"		
		92																	OUT ₄	"		"		
		93																	OUT ₅	"		"		
		94																	OUT ₆	"		"		
		95																	OUT ₇	"		"		
		96																	OUT ₈	"		"		
		97	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 μA	350 mA	350 mA	200 mA	200 mA	1.5	V	
		98																	OUT ₁	"		"		
		99																	OUT ₂	"		"		
$V_{CE}(\text{sat})$		100																	OUT ₃	"		"		
		101																	OUT ₄	"		"		
		102																	OUT ₅	"		"		
		103																	OUT ₆	"		"		
		104																	OUT ₇	"		"		
		105	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	250 μA	200 mA	200 mA	200 mA	200 mA	100 mA	1.3	V
		106																	OUT ₁	"		"		
		107																	OUT ₂	"		"		
		108																	OUT ₃	"		"		
		109																	OUT ₄	"		"		
$I_{IN}(\text{on})$		110																	OUT ₅	"		"		
		111																	OUT ₆	"		"		
		112																	OUT ₇	"		"		
		113	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	IN ₁	1180	2400	μA		
		114																	IN ₂	"		"		
		115																	IN ₃	"		"		
		116																	IN ₄	"		"		
		117																	IN ₅	"		"		
		118																	IN ₆	"		"		
		119																	IN ₇	"		"		
		120																	IN ₈	"		"		

TABLE III. Group A inspection for device type 10 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured limits		Unit	
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	
$T_A = +125^\circ C$	$I_{IN(off)}$	121	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	50 V	50V	50 V	500 μA		
		122																OUT ₁	OUT ₂	OUT ₃	OUT ₄	
		123																OUT ₅	OUT ₆	OUT ₇	OUT ₈	
		124																IN ₁	IN ₂	IN ₃	IN ₄	
		125																IN ₅	IN ₆	IN ₇	IN ₈	
		126																COM	OUT ₈	OUT ₇	OUT ₆	
		127																OUT ₅	OUT ₄	OUT ₃	OUT ₂	
		128																OUT ₁	OUT ₂	OUT ₃	OUT ₄	
	$V_{IN(on)}$	129	2.4 V															350 mA	350 mA	350 mA	350 mA	2.0 V
		130	2.4 V															IN ₁	IN ₂	IN ₃	IN ₄	
I_R		131																IN ₅	IN ₆	IN ₇	IN ₈	
		132																COM	COM	COM	COM	
		133																COM	COM	COM	COM	
		134																COM	COM	COM	COM	
		135																COM	COM	COM	COM	
		136																COM	COM	COM	COM	
		137																COM	COM	COM	COM	
		138																OUT ₁	OUT ₂	OUT ₃	OUT ₄	
		139																OUT ₅	OUT ₆	OUT ₇	OUT ₈	
		140																10.0 μA				
V_F		141																				
		142																				
		143																				
		144																				
		145																				
		146																				
		147																				
		148																				
		149																				
		150																				
hFE		151																				
		152																				
		153	IB_1	IB_2	IB_3	IB_4	IB_5	IB_6	IB_7	IB_8								1000				
		154																IB_1 - OUT_1	IB_2 - OUT_2	IB_3 - OUT_3	IB_4 - OUT_4	
		155																IB_5 - OUT_5	IB_6 - OUT_6	IB_7 - OUT_7	IB_8 - OUT_8	
		156																				
		157																				
		158																				
		159																				
		160																				

TABLE III. Group A inspection for device type 10 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured		Limits			
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	terminal	Min	Max
3 $T_A = -55^\circ C$	I_{CEX}	161	IN_1																				10.0	μA
		162	IN_2																				"	"
		163																					"	"
		164																					"	"
		165																					"	"
		166																					"	"
		167																					"	"
		168																					"	"
		3007	169	850 μA																			350 mA	μA
		170		850 μA																			350 mA	μA
VCE(sat)		171		850 μA																			350 mA	μA
		172																					"	"
		173																					"	"
		174																					"	"
		175																					"	"
		176																					"	"
		3007	177	550 μA																			200 mA	μA
		178		550 μA																			200 mA	μA
		179																					"	"
		180																					"	"
VCE(sat)		181																					"	"
		182																					"	"
		183																					"	"
		184																					"	"
		3007	185	350 μA																			100 mA	μA
		186		350 μA																			100 mA	μA
		187																					"	"
		188																					"	"
		189																					"	"
		190																					"	"
$I_{IN(on)}$		191																					"	"
		192																					"	"
		193	3.0 V																				"	"
		194		3.0 V																			"	"
		195																					"	"
		196																					"	"
		197																					"	"
		198																					"	"
		199																					"	"
		200																					"	"

TABLE III. Group A inspection for device type 10 - Continued.

Subgroup	Symbol	MIL-STD-883 method	Pin number and signal designation																Measured terminal	Min	Max	Limits
			Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	
3 $T_A = -55^\circ C$	$I_{IN(off)}$	201	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	25 μA	50 V	50V	500 μA		
		202	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	"	"	
		203	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₂	"	"	
		204	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	"	"	
		205	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₄	"	"	
		206	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	"	"	
		207	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₆	"	"	
		208	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	"	"	
		209	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	3.0 V	350 mA	350 mA	350 mA	
		210	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₈	"	"	
$V_{IN(on)}$	I_R	211	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	2.0 V	"	"	
		212	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	"	"	
		213	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₂	"	"	
		214	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	"	"	
		215	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₄	"	"	
		216	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	"	"	
		217	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₆	"	"	
		218	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	"	"	
V_F	hFE	219	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	10.0 μA	"	"	
		220	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	"	"	
		221	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	"	"	
		222	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	"	"	
		223	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	"	"	
		224	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	"	"	
		225	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	"	"	
		226	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	COM	"	"	
IB_1	IB_2	227	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₁	"	"	
		228	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₂	"	"	
		229	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₃	"	"	
		230	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₄	"	"	
		231	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₅	"	"	
		232	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₆	"	"	
		233	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₇	"	"	
		234	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT ₈	"	"	
IB_3	IB_4	235	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IB ₁ -OUT ₁	500	"	
		236	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IB ₂ -OUT ₂	"	"	
		237	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IB ₃ -OUT ₃	"	"	
		238	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IB ₄ -OUT ₄	"	"	
		239	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IB ₅ -OUT ₅	"	"	
		240	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IB ₆ -OUT ₆	"	"	
		"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IB ₇ -OUT ₇	"	"	
		"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IB ₈ -OUT ₈	"	"	

TABLE III. Group A inspection for device type 10 - Continued.

Subgroup	Symbol	ML-STD-883 method	Test no.	Pin number and signal designation																Measured terminal	Min	Max	Unit	
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16					
$T_A = +25^\circ C$	t_{PLH}	3003 Fig. 4	241	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	IN ₈	GND	COM	OUT ₈	OUT ₇	OUT ₆	OUT ₅	OUT ₄	OUT ₃	OUT ₂	OUT ₁	OUT	OUT	ns
			242	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	IN ₈	0 V	"	"	"	"	"	"	"	"	IN ₁ -OUT ₁	750	ns	
			243	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₂ -OUT ₂	"	"	
			244	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₃ -OUT ₃	"	"	
		245 Fig. 4	245	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₄ -OUT ₄	"	"	
			246	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₅ -OUT ₅	"	"	
			247	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₆ -OUT ₆	"	"	
			248	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₇ -OUT ₇	"	"	
	t_{PHL}	3003 Fig. 4	249	IN ₁	IN ₂	IN ₃	IN ₄	IN ₅	IN ₆	IN ₇	IN ₈	"	"	"	"	"	"	"	"	"	IN ₈ -OUT ₈	"	"	
			250	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OUT	OUT	ns	
			251	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₁ -OUT ₁	"	"	
			252	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₂ -OUT ₂	"	"	
		253 Fig. 4	253	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₃ -OUT ₃	"	"	
			254	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₄ -OUT ₄	"	"	
			255	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₅ -OUT ₅	"	"	
			256	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	IN ₆ -OUT ₆	"	"	

NOTE: Pins not designated are open.

4.4 Technology Conformance inspection (TCI). Technology conformance inspection shall be in accordance with MIL-PRF-38535 and herein for groups A, B, C, and D inspections (see 4.4.1 through 4.4.4).

4.4.1 Group A inspection. Group A inspection shall be in accordance with table III of MIL-PRF-38535 and as follows:

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, 6, 7, 8, 10, and 11 in table I shall be omitted.

4.4.2 Group B inspection. Group B inspection shall be in accordance with table II of MIL-PRF-38535.

4.4.3 Group C inspection. Group C inspection shall be in accordance with table IV of MIL-PRF-38535 and as follows:

- a. End point electrical parameters shall be as specified in table II herein.
- b. The steady-state life test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.

4.4.4 Group D inspection. Group D inspection shall be in accordance with table V of MIL-PRF-38535. End point electrical parameters shall be as specified in table II herein.

4.5 Methods of inspection. Methods of inspection shall be specified and as follows.

4.5.1 Voltage and current. All voltage values given are referenced to the microcircuit ground terminal of the device under test (DUT). Currents values given for conventional current and are positive when flowing into the referenced terminal.

4.5.2 Life test and burn-in cooldown procedure. When devices are measured at +25°C following application of the steady-state life or burn-in test condition, they shall be cooled within 10°C of their power stable condition at room temperature prior to removal of the bias.

5. PACKAGING

5.1 Packaging requirements. For acquisition purposes, the packaging requirements shall be as specified in the contract or order (see 6.2). When actual packaging of materiel is to be performed by DoD personnel, these personnel need to contact the responsible packaging activity to ascertain requisite packaging requirements. Packaging requirements are maintained by the Inventory Control Point's packaging activity within the Military Department of Defense Agency, or within the Military Department's System Command. Packaging data retrieval is available from the managing Military Department's or Defense Agency's automated packaging files, CD-ROM products, or by contacting the responsible packaging activity.

TABLE IV. Group C end-point electrical parameters. TA = +25°C

Test	Limits		Delta		Unit
	Min	Max	Min	Max	
I _{CEX}	---	10.0	-0.5	+0.5	µA
h _{FE}	1000	---	-25%	25%	---

6. NOTES

6.1 Intended use. Microcircuits conforming to this specification are intended for original equipment design applications and logistic support of existing equipment.

6.2 Acquisition requirements. Acquisition documents should specify the following:

- a. Title, number, and date of the specification.
- b. Pin and compliance identifier, if applicable (see 1.2).
- c. Requirements for delivery of one copy of the conformance inspection data pertinent to the device inspection lot to be supplied with each shipment by the device manufacturer, if applicable.
- d. Requirements for certificate of compliance, if applicable.
- e. Requirements for notification of change of product or process to acquiring activity in addition to notification of the qualifying activity, if applicable.
- f. Requirements for failure analysis (including required test condition of MIL-STD-883, method 5003), corrective action and reporting of results, if applicable.
- g. Requirements for product assurance options.
- h. Requirements for special carriers, lead lengths, or lead forming, if applicable. These requirements should not affect the part number. Unless otherwise specified, these requirements will not apply to direct purchase by or direct shipment to the Government.
- i. Requirements for "JAN" marking.
- j. Packaging requirements (see 5.1).

6.3 Superseding information. The requirements of MIL-M-38510 have been superseded to take advantage of the available Qualified Manufacturer Listing (QML) system provided by MIL-PRF-38535. Previous references to MIL-M-38510 in this document have been replaced by appropriate references to MIL-PRF-38535. All technical requirements now consist of this specification and MIL-PRF-38535. The MIL-M-38510 specification sheet number and PIN have been retained to avoid adversely impacting existing government logistics systems and contractor's parts lists.

6.4 Qualification. With respect to products requiring qualification, awards will be made only for products which are, at the time of award of contract, qualified for inclusion in Qualified Manufacturers List QML-38535 whether or not such products have actually been so listed by that date. The attention of the contractors is called to these requirements, and manufacturers are urged to arrange to have the products that they propose to offer to the Federal Government tested for qualification in order that they may be eligible to be awarded contracts or purchase orders for the products covered by this specification. Information pertaining to qualification of products may be obtained from DSCC-VQ, 3990 E. Broad Street, Columbus, Ohio 43123-1199.

6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535, MIL-STD-1331, and as follows:

GND	Ground zero voltage potential
I _{CEx}	Collector cutoff current
V _{IN}	Voltage level at an input terminal
V _F	Forward voltage drop
V _{CE}	Collector emitter saturation voltage
I _{IN}	Current flowing into an input terminal
I _R	Clamp diode leakage current
V _F	Clamp diode forward voltage

6.6 Logistic support. Lead materials and finishes (see 3.3) are interchangeable. Unless otherwise specified, microcircuits acquired for Government logistic support will be acquired to device class B (see 1.2.2), lead material and finish A (see 3.4). Longer length leads and lead forming should not affect the part number.

6.7 Substitutability. The cross-reference information below is presented for the convenience of users. Microcircuits covered by this specification will functionally replace the listed generic-industry type. Generic-industry microcircuit types may not have equivalent operational performance characteristics across military temperature ranges or reliability factors equivalent to MIL-M-38510 device types and may have slight physical variations in relation to case size. The presence of this information should not be deemed as permitting substitution of generic-industry types for MIL-M-38510 types or as a waiver of any of the provisions of MIL-PRF-38535.

Military device type	Generic-industry type
01	2001
02	2002
03	2003
04	2004
05	2005
06	2801
07	2802
08	2803
09	2804
10	2805

6.8 Changes from previous issue. Marginal notations are not used in this revision to identify changes with respect to the previous issue, due to the extensiveness of the changes.

Custodians:	Preparing activity:
Army – CR	DLA - CC
Navy - EC	
Air Force - 11	Project 5962-2060
NASA - NA	
DLA – CC	
Review activities:	
Army - MI, SM	
Navy - AS, CG, SH, TD	
Air Force – 03, 19, 99	

NOTE: The activities listed above were interested in this document as of this date of this document. Since organizations and responsibilities can change, you should verify the currency of the information above using the ASSIST Online database at www.dodssp.daps.mil.